

# XGS Family

## Advance Information

# XGS 5000, XGS 3000, XGS 2000 and XGS 1300 Global Shutter CMOS Image Sensors

### Description

The XGS CMOS image sensor family provides high resolution, high performance global shutter image capture. The family comes in different resolutions in a single package, 1.3, 2, 3 and 5 Megapixels with up to 2/3-inch optical format. The 16 mm x 16 mm package makes the XGS family particularly suited for integration in 29 mm x 29 mm camera formats. The high speed, 12-bit output maximally leverages interfaces such as USB 3.2, Thunderbolt™ 2 and 10 GigE.

Image data is read out through a column ADC architecture and then transferred over a HiSPi interface. On-chip logic, programmable via the serial interface, generates internal timing for integration and readout control. Up to three register configurations can be programmed and sequentially enabled (frame by frame) using a single command over the control interface.

**Table 1. KEY PERFORMANCE PARAMETERS**

Parameter	Typical Value	
Optical Format	XGS 5000	2/3-inch (10.6 mm Diagonal)
	XGS 3000	1.2-inch (8.2 mm Diagonal)
	XGS 2000	1/1.25-inch (7.3 mm Diagonal)
	XGS 1300	1/3.2-inch (5.3 mm Diagonal)
Active Pixels	XGS 5000	2592 (H) x 2048 (V)
	XGS 3000	2048 (H) x 1538 (V)
	XGS 2000	1920 (H) x 1200 (V)
	XGS 1300	1280 (H) x 1024 (V)
Pixel Size	3.2 μm	
Color Filter Array	Monochrome, Bayer	
Shutter Type	Global Shutter	
Input Clock	32.4 MHz	
Output Interface	HiSPi (16 Lanes – 777.6 Mbps/lane)	
Frame Rate (12-bit)	16 Lanes (–X4)	
	XGS 5000	132 *
	XGS 2000	220 *
	XGS 1300	254
	4 Lanes (–X5)	
	XGS 5000	43 *
	XGS 3000	57 *
	XGS 2000	72 *
Read Noise	3.8 e <sub>-</sub> (1x) *	
SNR <sub>MAX</sub>	TBD	
Dynamic Range	68 dB *	
Supply Voltages	1.2V, 2.8 V, 3 V (0.4 V, 1.8 V Optional)	
Power Consumption	TBD	
Operating Temp.	–40°C to 85°C (Junction)	
Package	163-pin iLGA (Inspectable Land Grid Array)	

\*Preliminary values subject to change



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### Features

- On-chip 12-bit Column ADCs
- Companding Mode for All Resolutions
- Data Interface: 16-lane HiSPi (Scalable Low-Voltage Signaling)
- Configurable Number of HiSPi Lanes: 16, 12, 8 or 4 Lanes
- Four-wire Serial Interface (SPI)
- Triggered Integration and Readout Control
- Programmable Control for up to 8 Regions of Interest (ROI)
- Context Switching
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

### Applications

- Machine Vision
- Security
- Intelligent Transportation Systems (ITS)
- Broadcasting
- Medical
- Scientific

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## ORDERING INFORMATION

**Table 2. ORDERABLE PART NUMBERS** (Note 2, Note 3)

Part Number	Product Description			Speed Grade	Resolution (H x V)
NOIX4SN5000B-LTI (Note 1)	5 Mp	Mono	Production Device	16 lanes	2592 x 2048
NOIX4SE5000B-LTI (Note 1)	5 Mp	Color	Production Device		
NOIX5SN5000B-LTI (Note 1)	5 Mp	Mono	Production Device	4 lanes	
NOIX5SE5000B-LTI (Note 1)	5 Mp	Color	Production Device		
NOIX4SN5000B-LTI (Note 1)	5 Mp	Mono	Production device	16 lanes	2592 x 2048
NOIX4SN5000BLFB-GEVB	5 Mp	Mono	Engineering device	16 lanes	
NOIX4SE5000B-LTI (Note 1)	5 Mp	Color	Production device	16 lanes	
NOIX4SE5000BLFB-GEVB	5 Mp	Color	Engineering device	16 lanes	
NOIX5SN5000B-LTI (Note 1)	5 Mp	Mono	Production device	4 lanes	
NOIX5SE5000B-LTI (Note 1)	5 Mp	Color	Production device	4 lanes	
NOIX5SN3000B-LTI (Note 1)	3 Mp	Mono	Production Device	4 lanes	2048 x 1538
NOIX5SE3000B-LTI (Note 1)	3 Mp	Color	Production Device		
NOIX4SN2000B-LTI (Note 1)	2 Mp	Mono	Production Device	16 lanes	1920 x 1200
NOIX4SE2000B-LTI (Note 1)	2 Mp	Color	Production Device		
NOIX5SN2000B-LTI (Note 1)	2 Mp	Mono	Production Device	4 lanes	
NOIX5SE2000B-LTI (Note 1)	2 Mp	Color	Production Device		
NOIX4SN1300B-LTI (Note 1)	1.3 Mp	Mono	Production Device	16 lanes	1280 x 1024
NOIX4SE1300B-LTI (Note 1)	1.3 Mp	Color	Production Device		

1. Production Device part numbers are listed for informational purpose only. Production Device part numbers are not available for orders at this time. Please contact ON Semiconductor for availability dates.
2. See the ON Semiconductor Device Nomenclature document (TND310/D) for a full description of the naming convention used for image sensors. For reference documentation, including information on evaluation kits, please visit our web site at [www.onsemi.com](http://www.onsemi.com).
3. All devices listed in Table 2 are equipped with microlenses and optimized for a 0° Chief Ray Angle (zero-shift placement).

**Table 3. ORDERING INFORMATION EVALUATION KITS**

Part Number	Product Description	Additional Information
TBD	TBD	TBD
AGBAN6CS-GEVK	Frame Buffer Demo Board	AP21088 including Power Adapter
AGB1N0CS-GEVK	Demo 3 Board	FPGA Base Board including USB Cable and Tripod

**GENERAL DESCRIPTION**

The XGS5000 family from ON Semiconductor covers four resolutions: 5 Mp, 3 Mp, 2 Mp, 1.3 Mp, and three speed grades (16, 8 or 4 HiSPi lanes). Refer to Table 2 for an overview of the available combinations of resolution and speed. Various operating modes enable flexible sensor operation to meet application specific requirements such as reduced data rate implemented by HiSPi lane multiplexing.

**FUNCTIONAL OVERVIEW**

The XGS family features global shutter technology for accurate capture of moving objects. Global shutter requires all pixels to simultaneously integrate light although the subsequent readout is sequential. Note that integration and readout can occur in parallel; while reading out one frame, integration of the next frame can start (i.e. *pipelined operation*). The core of the sensor is the 5 Mp active pixel array.

Figure 1 gives an overview of the major functional blocks of the XGS sensor.

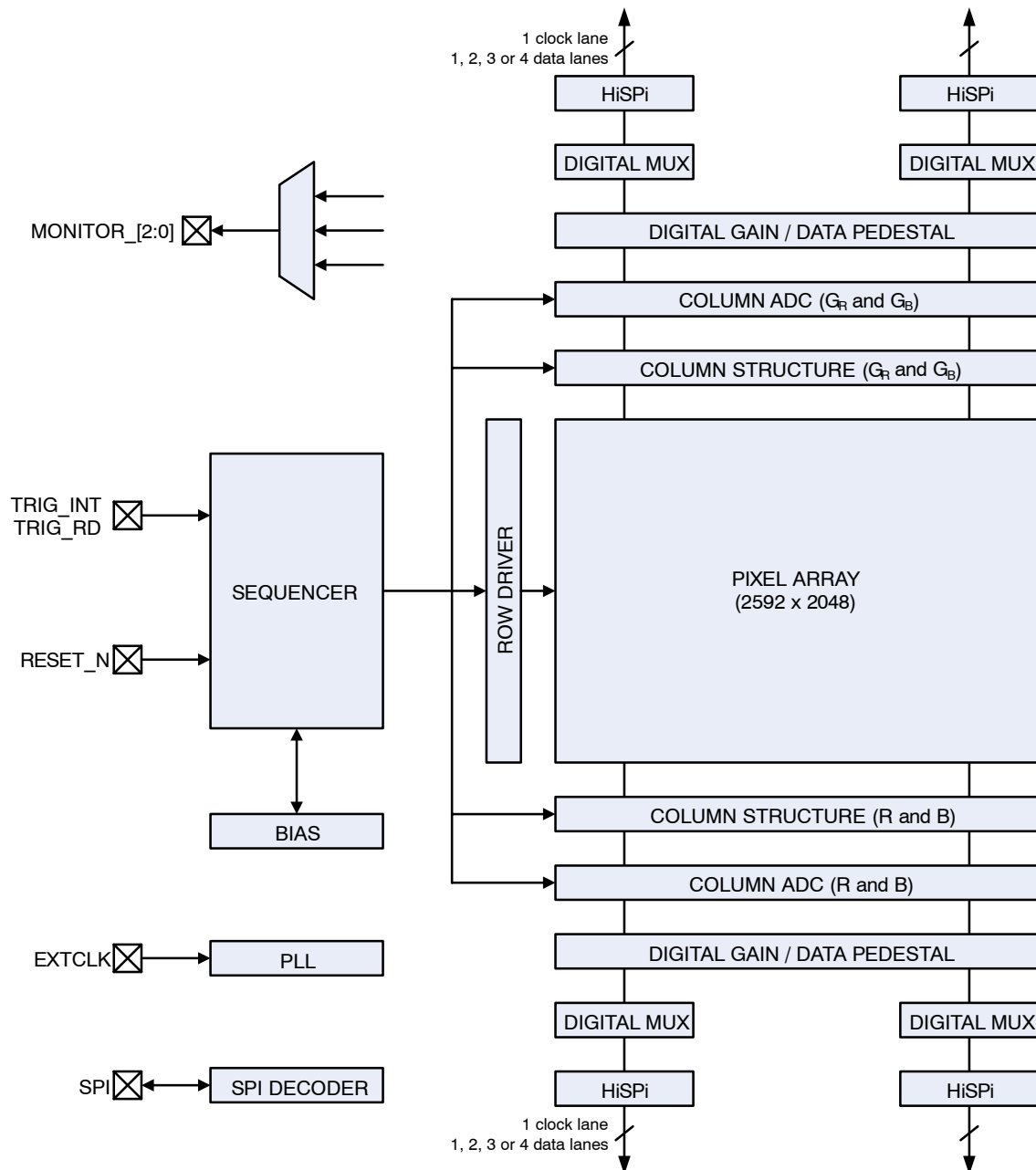


Figure 1. Functional Block Diagram (XGS 5000)

The on-chip logic, programmable through a four-wire serial interface, generates all internal timing for integration control and frame readout. Once a row has been read, the data from the columns is sequenced through an analog signal chain (providing coarse analog gain) and then through a 12-bit column ADC. The data from the ADCs is first stored in the on-chip column memory bank prior to being processed by the digital data path (which provides additional data processing including digital gain and offset). The digital multiplexer can be configured to reduce the number of active data lanes. The maximum output pixel rate on a single lane is 64.8 Megapixel per second, corresponding to a clock rate of 32.4 MHz.

Advanced trigger functions enable synchronization to external events (triggered master and slave mode) but also allow synchronizing image readout with the host (receiver) on a frame or line basis (triggered frame or line readout). The sensor supports configuration of up to eight independent ROIs and up to three register configurations (*contexts*) can be programmed and sequentially applied (frame by frame) with a single command over the control interface.

Refer to Figure 1 for the functional blocks described hereafter.

- **Serial Peripheral Interface (SPI)**  
User interaction with the sensor is handled through the four-wire SPI. The uploaded control data is stored in the SPI registers and distributed to the relevant blocks.
- **EXTCLK**  
The nominal input clock frequency is 32.4 MHz. This clock serves as the base clock for the derived clock domains required by the internal sub-blocks and HiSPi output interface.
- **Phase-locked Loop (PLL)**  
The on-chip phase-locked loop generates all the internal system clocks, including the HiSPi clock.
- **Bias Generator**  
The bias generator generates the required reference currents used by the on-chip blocks.
- **Sequencer**  
The sequencer generates the sensor timing and controls the image core which contains all pixels, driving and readout circuits. It controls the ADC circuits and provides the necessary information to the digital data path. The sequencer operating and readout modes (ROI readout, subsampling...) can be configured through the SPI interface. The readout parameters are synchronized to frame boundaries to support dynamic reconfiguration without generating any corrupted images.
- **Row Driver**  
The row drivers generate the reset and select signals used to operate the pixel array.

- **Monitor Pins**  
The sequencer can communicate its internal states through the monitor output pins.
- **Column Structure**  
The column structure contains the analog circuits necessary to ensure a proper transfer of the signal to the column ADC. This structure includes the column amplifiers which can be used to apply analog gain to the signal before these are converted by the ADCs. The sensor supports analog gain of 1x, 2x and 4x. The analog gain is applied globally to all pixels.
- **Column ADC**  
For each column, a 12-bit ADC converts the analog signal into a digital value.
- **Digital Gain**  
A linear, digital gain ranging from 1/32x up to 2x can be configured separately for each color channel in steps of 1/32.
- **Data Pedestal**  
This block adds a user programmable, per color channel digital offset to the pixel values.
- **Digital Mux**  
This block handles the lane multiplexing which can be used to reduce the number of output lanes.
- **HiSPi**  
The 16 HiSPi lanes are laid out in four identical HiSPi blocks. Each block consists of four data lanes and one clock lane. The number of active data lanes (1, 2, 3 or 4) depends on the selected multiplex mode.

## PIXEL DATA FORMAT

### PIXEL ARRAY STRUCTURE

The XGS 5000 active pixel array consists of 2592 columns by 2048 rows of optically active pixels. Refer to Table 1 for the active resolution of XGS 5000, XGS 3000, XGS 2000 and XGS 1300. As shown in Figures 2 through 5, the active array is surrounded by a four-pixel wide collar of interpolation pixels for color interpolation purposes. The entire active array (including interpolation pixels) is isolated from the black reference pixels by a collar of dummy pixels. The purpose of these dummy pixels is to improve the image uniformity within the active area. The complete pixel array, including all dummy, black and interpolation pixels, consists of a total of 2688 columns and 2078 rows (1538 rows for XGS3000, 1200 rows for XGS2000 and 1024 rows for XGS1300). The sensor's active pixel array is shown with the first pixel in the bottom left corner (refer to Figures 2 through 5).

The color version of the sensor has a Bayer Color Filter Array (CFA) placed on top of the pixels. The mapping of the CFA with respect to the active pixel array is shown in Figure 2 through 5.

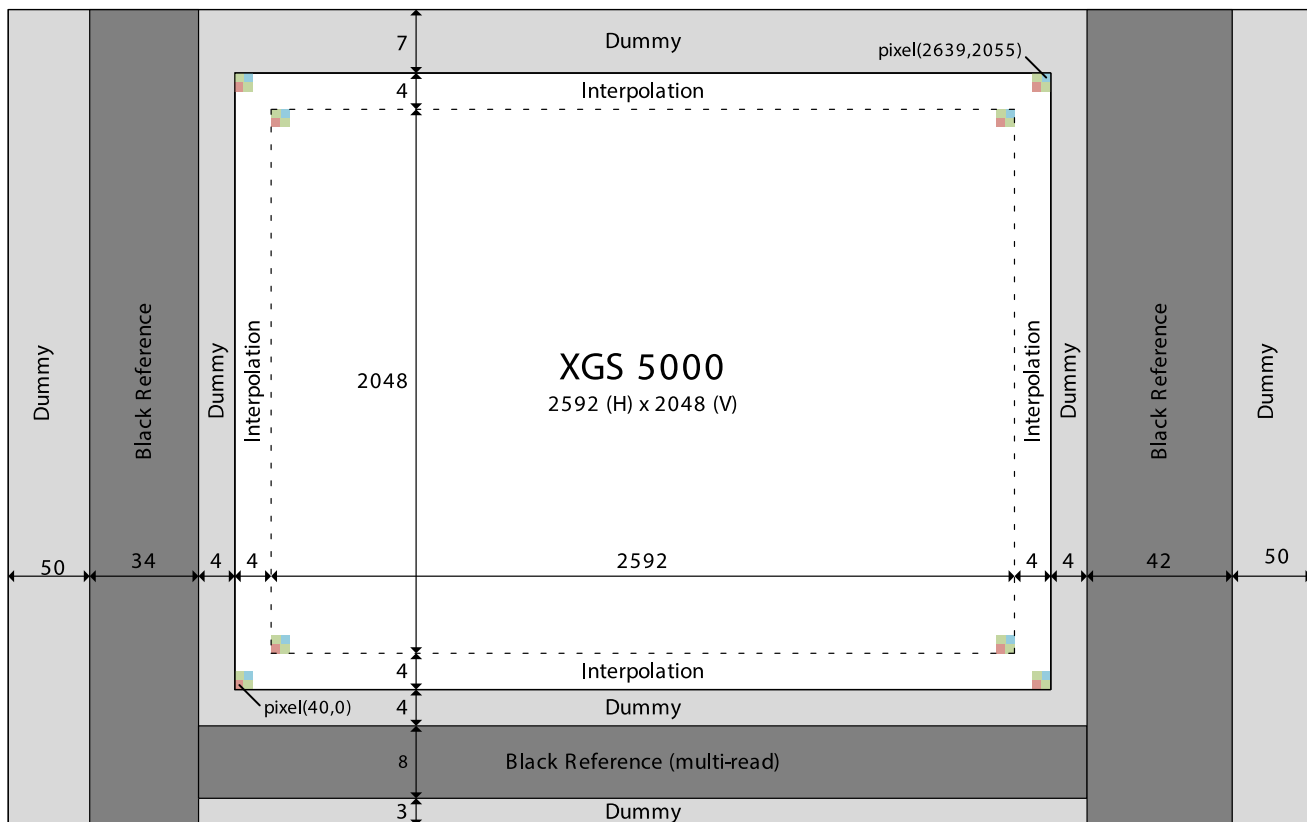
**PIXEL ARRAY READOUT**

The electrical black reference lines are read out at the start of every frame. The number of lines to be read out is configurable through the M lines configuration (configurable for each context). The ROI configurations are processed after the black reference lines. The lines accessible through the window configurations are limited to the active area region, including interpolation rows. Note that the windows are configured in logical kernel addresses. A kernel contains four image lines and the kernel with logical address 0 corresponds to the lines with physical addresses:

- 15:18 for XGS5000
- 270:273 for XGS3000
- 439:442 for XGS2000
- 527:230 for XGS1300

Each window configuration consists of two parameters: a start address and window height. The configured windows are reordered such that the ROI with the smallest start address is read out first. After completion of the readout of the first ROI, the line address pointer will be initialized to the start address of the next ROI. For overlapping windows, the sequencer will just continue the readout. Note that the overlapping part is read out only once.

Lines are read out from left to right and each line contains different types of pixels. A line starts with 2 dummy pixels followed by 34 electrical black reference pixels. The regular image pixels are preceded and followed by 4 dummy pixels. Dummy pixels are identical to the regular pixels, but may deviate in performance. Therefore the dummy pixels should be discarded. Each line is ended by another 42 black reference pixels followed by 2 dummy pixels.



**Figure 2. XGS 5000 Pixel Array**

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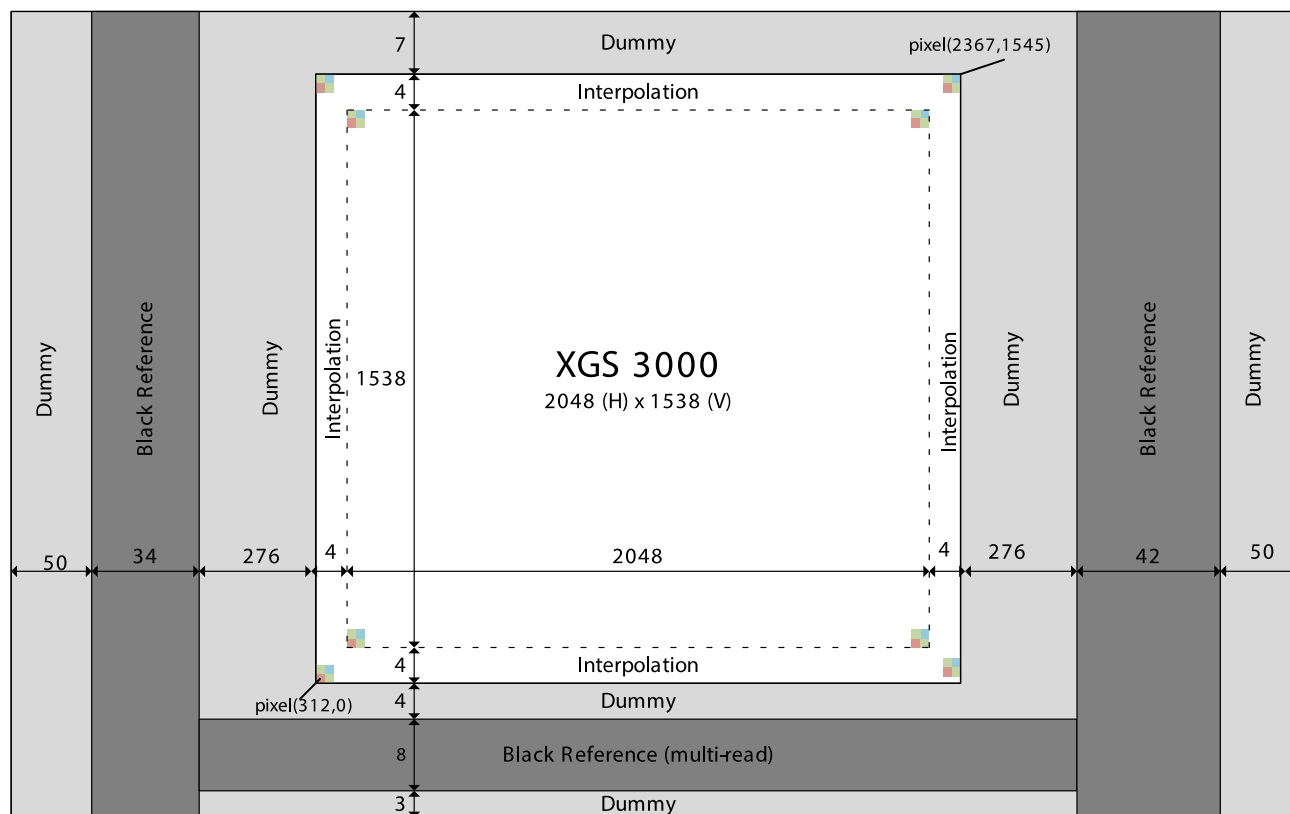


Figure 3. XGS 3000 Pixel Array

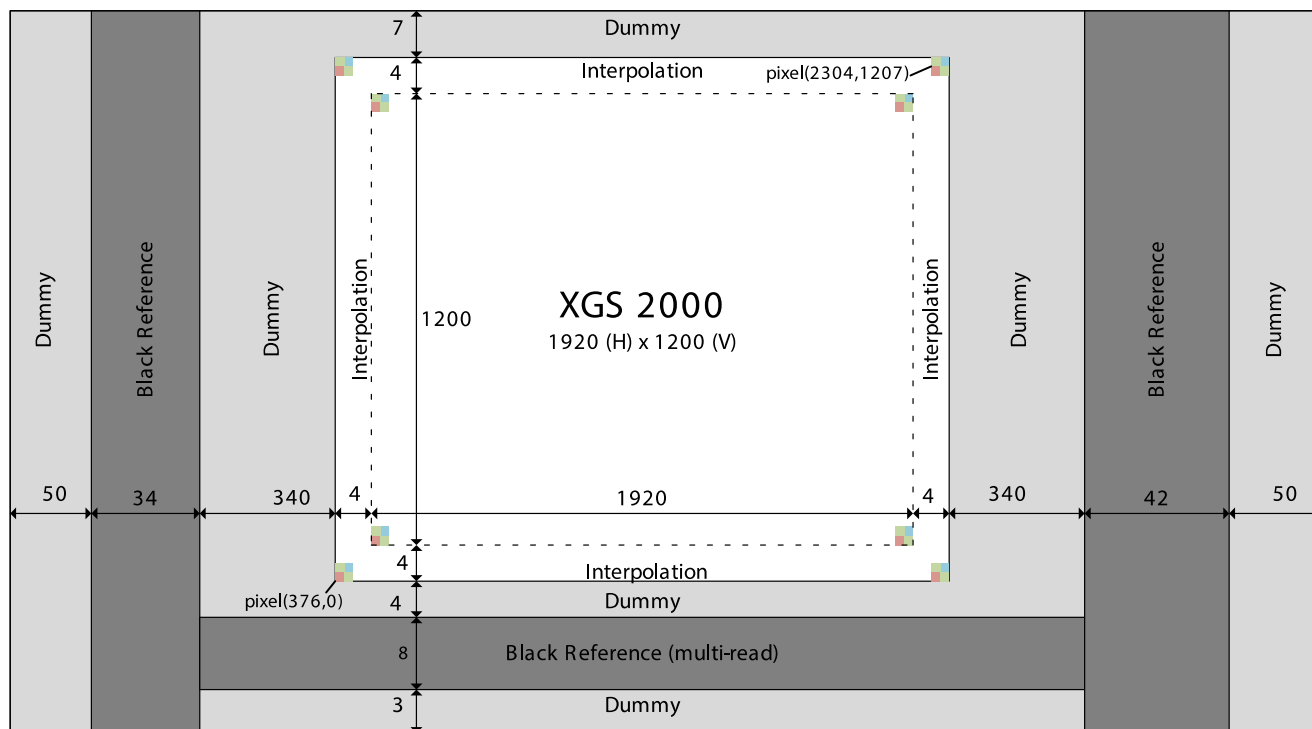


Figure 4. XGS 2000 Pixel Array

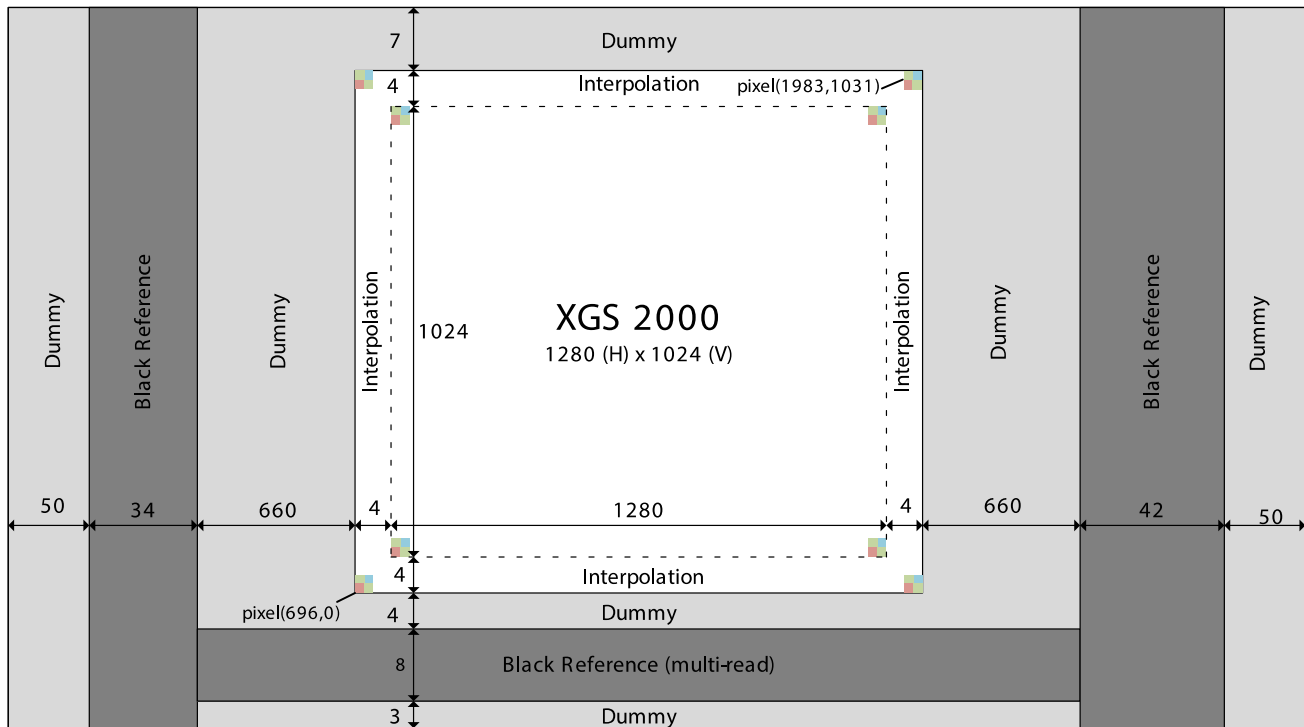


Figure 5. XGS 1300 Pixel Array

### Readout Order

Frame readout starts by setting the read address to the first row of the configured ROI. Once the row is read, the read address is incremented and the next row is read. This cycle continues until the last row of the ROI has been read. The incremental addressing scheme is depicted in Figure 6.

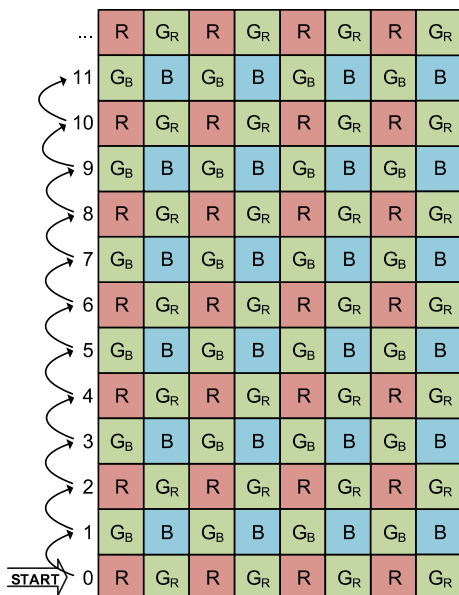


Figure 6. Incremental Row Addressing Sequence

### Subsampled Readout

During subsampled readout only a subset of the pixel array is read out, enabling faster read out with the same field of view but at the expense of reduced image resolution. In order to support subsampling on both monochrome and color sensors, XGS supports two different subsampling schemes:

#### 1. Read One Skip One

In this mode, one out of four pixels is selected for readout by selecting every other line and column in the image array. The Read-One-Skip-One mode is depicted in Figure 7 below. This subsampling mode does not preserve the Bayer pattern so it is recommended for monochrome devices only.

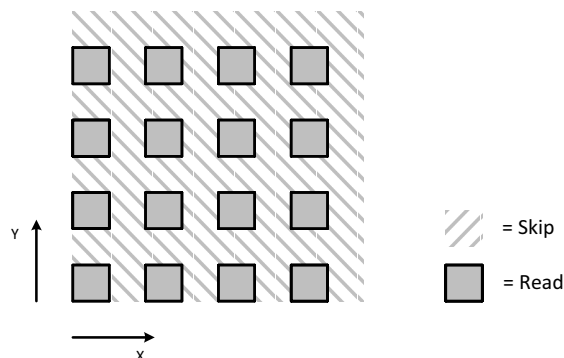


Figure 7. Monochrome Subsampling (Read-1-Skip-1)

#### 2. Read Two Skip Two

The Read-Two-Skip-Two subsampling scheme is recommended for color sensors as it preserves the Bayer pattern. When using the Read-Two-Skip-Two scheme, the sensor first reads two rows and then skips two rows. From each row being read, first two adjacent pixels will be read, then two will be skipped. This readout scheme is depicted in Figure 8.

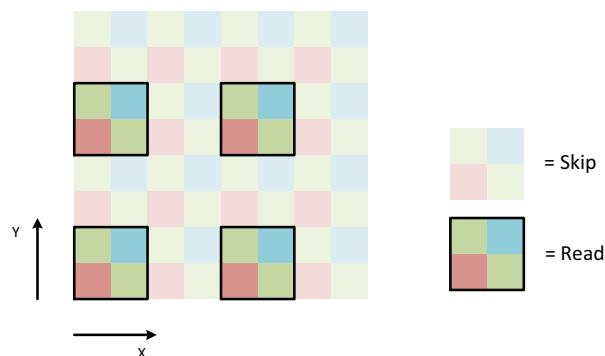


Figure 8. Color Subsampling (Read-2-Skip-2)

### Reverse Readout

XGS supports reverse readout in the vertical (Y-) direction. If `active_config_reg.active_reversed` is set to 1, the ROIs will be read top to bottom instead of the default (`active_config_reg.active_reversed = 0`) bottom to top readout direction.



## CONFIGURATION AND PINOUT

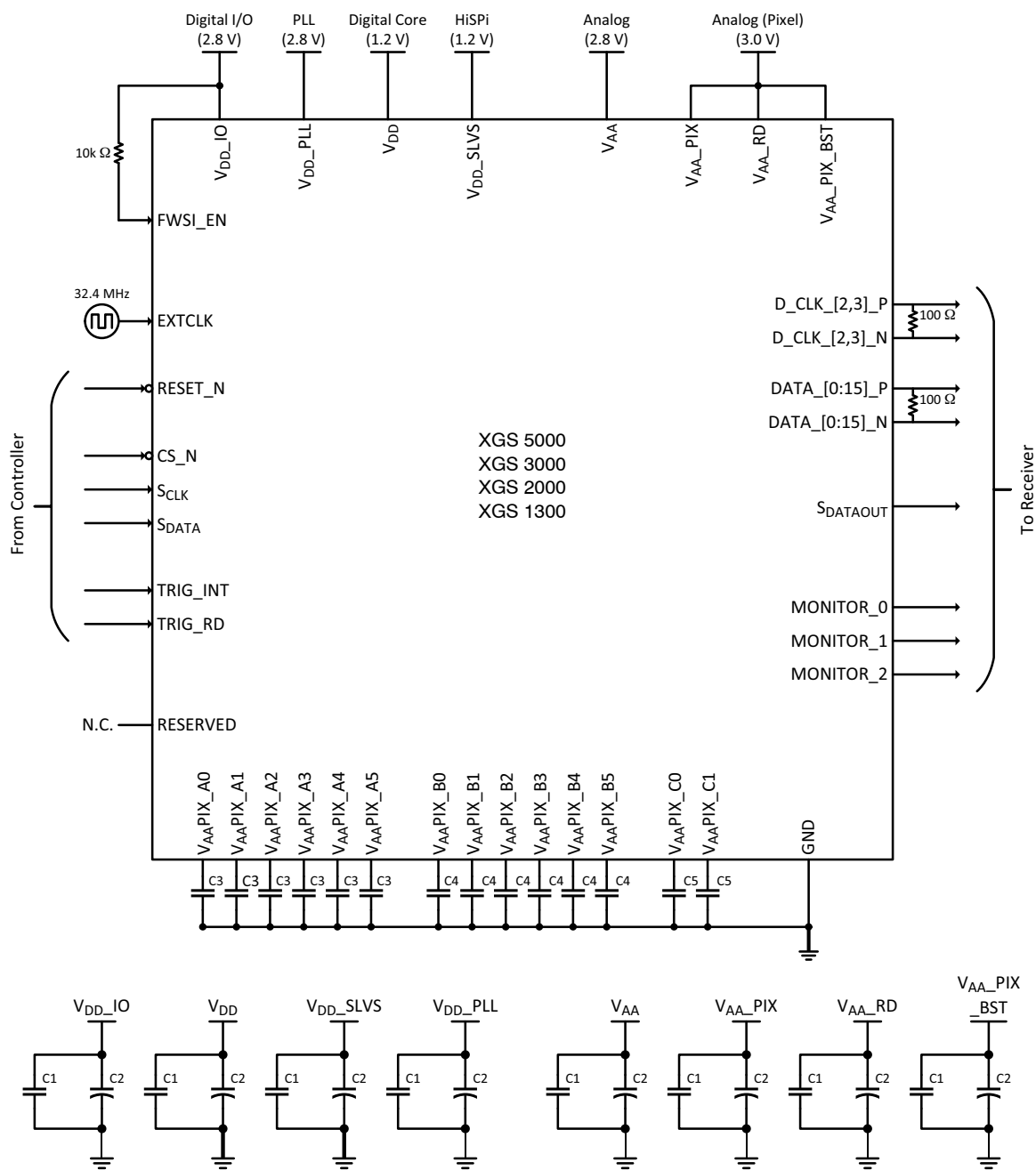
### TYPICAL CONFIGURATIONS

Figure 9 below shows a typical configuration for the XGS image sensor. Pin connections to (and from) the sensor and power supply configurations are shown in the figure below. The recommended decoupling capacitors are listed in Table 4.

#### *Configuration Example:*

- $V_{DD\_SLVS} = 1.2\text{ V}$  (or  $0.4\text{ V}$ );  $V_{DD} = 1.2\text{ V}$ ;  $V_{DD\_IO} = 2.8\text{ V}$  ( $1.8\text{ V}$ );  $V_{DD\_PLL} = 2.8\text{ V}$ ;
- $V_{AA} = 2.8\text{ V}$ ;  $V_{AA\_PIX} = 3.0\text{ V}$ ;  $V_{AA\_RD} = 3.0\text{ V}$ ;  $V_{AA\_PIX\_BST} = 3.0\text{ V}$
- 16 data lanes + 2 clock lanes

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**Figure 9. Typical Configuration**

1. All power supplies must be adequately decoupled (see Table 4) Decoupling.
2. In this example, only 2 (out of 4) HiSPi clock lanes are used; D\_CLK\_2 to sample data on the even data lanes (top readout) and D\_CLK\_3 to sample data on the odd data lanes (bottom readout).
3. The active HiSPi lanes need to be terminated using 100  $\Omega$  resistors placed as close to the receiver as possible.
4. Unused HiSPi outputs (data and/or clock lanes) must be left floating.
5. It is highly recommended to route the monitor signals to the receiver (FPGA) for debugging purposes. If the MONITOR outputs are not used, they must be left floating.
6. If the TRIGGER inputs are not used, tie them to GND.
7. No distinction is made between analog and digital ground (internally shorted).
8. FWSI\_EN must be connected to VDD\_IO through a 10k resistor.
9. I/O signals voltage must be configured to match VDD\_IO voltage to minimize any leakage currents.
10. Digital inputs RESET\_N and CS\_N are both active low.

Capacitor	Recommended Capacitor Value (μF)	Capacitor	Recommended Capacitor Value (μF)
C1, C5	0.1	C3	0.1 + 4.7
C2	10	C4	0.1 + 2.2

	C	D	E	F	G	H	J	K	L	M	N	P	R	T		
16	GND	GND	DVDD1V2	VDDSLVS2	GND	DVDD1V2	VDDSLVS2	GND	DVDD1V2	VDDSLVS2	AVDD	VDDIO2V8R1V8	GND	GND	16	
15	GND	GND	DATA_2_P	GND	DATA_6_P	DATA_10_P	GND	DATA_14_P	GND	GND	GND	VREF1_TOP	GND	GND	15	
14	AVDD	VAA_PIX	DATA_2_N	D_CLK_0_P	DATA_6_N	DATA_10_N	D_CLK_2_P	DATA_14_N	GND	GND	GND	VAA_PIX	AVDD	VAA_RD	14	
13	VAA_RD	DVDD1V2	DATA_0_P	D_CLK_0_N	DATA_4_P	DATA_8_P	D_CLK_2_N	DATA_12_P	GND	GND	GND	ATEST_TOP	AVDD	VRESFD_LO1	13	
12	GND	VAAHV_NPIX	DATA_0_N	DVDD1V2	DATA_4_N	DATA_8_N	DVDD1V2	DATA_12_N	GND	DVDD1V2	GND	GND	VAA_PIX_BOOSTER	VRESFD_HI	12	
11	VDDIO2V8R1V8	SDATA	TRIGGER2	TRIGGER0	TEST					GND	GND	VTX1_HI	VRESFD_LO2	VSG_HI	11	
10	VDD_PLL	FWSL_EN	SDATAOUT	TRIGGER1	DSPARE2					AVDD	AVDD	VTX0_HI	VRESPD_HI	GND	10	
9	VDDIO2V8R1V8	EXTCLK	CS	SCLK	DSPARE1					AVDD	AVDD	VRESPD_LO1	VTX0_LO1	AVDD	9	
8	VDDIO2V8R1V8	MONITOR1	MONITOR0	RESET_B	DSPARE0							GND	VTX1_LO2	VSG_LO1	VPSUB_LO	8
7	GND	MONITOR2	DATA_1_N	DVDD1V2	DATA_5_N	DATA_9_N	DVDD1V2	DATA_13_N	GND	DVDD1V2	GND	GND	VAA_PIX_BOOSTER	TX1_LO1	7	
6	VAA_RD	DVDD1V2	DATA_1_P	D_CLK_1_N	DATA_5_P	DATA_9_P	D_CLK_3_N	DATA_13_P	GND	GND	GND	ATEST_BTM	AVDD	VRS_HI	6	
5	AVDD	VAA_PIX	DATA_3_N	D_CLK_1_P	DATA_7_N	DATA_11_N	D_CLK_3_P	DATA_15_N	GND	GND	GND	VAA_PIX	AVDD	VAA_RD	5	
4	NC	NC	DATA_3_P	GND	DATA_7_P	DATA_11_P	GND	DATA_15_P	GND	GND	GND	VREF1_BOT	GND	GND	4	
3	NC	NC	DVDD1V2	VDDSLVS1	GND	DVDD1V2	VDDSLVS1	GND	DVDD1V2	VDDSLVS1	AVDD	VDDIO2V8R1V8	GND	GND	3	

GROUND

POWER

DIFFERENTIAL OUTPUT

CMOS I/O

**NOTE:** To obtain the corresponding pin position for the XGS12000 family, you should add 2 letters and 2 numbers to the XGS5000 family pin position. For example pin location A1 on XGS5000 corresponds to pin location C3 on XGS1200.

PIN LIST

Table 5. PIN DESCRIPTIONS (163-PIN LGA PACKAGE)

Name	LGA Pin Name	Type	Description
GND	A5, A10, A13, D2, D13, E1, E14, G2, G13, H1, H14, J2, J3, J4, J5, J10, J11, J12, J13, K2, K3, K4, K9, K11, K12, K13, L2, L3, L4, L5, L6, L9, L10, L11, L12, L13, M5, M10, N1, N13, P8	Ground	Ground
V <sub>DD_PLL</sub>	C10	Power	PLL Power Supply
V <sub>AA</sub>	M13, A3, N3, N4, P7, L7, K7, L8, K8, N11, N12, A12, L14	Power	Analog Supply
V <sub>AA_RD</sub>	A4, A11, P3, P12	Power	Analog Supply for Row Driver
V <sub>DD_IO</sub>	A6, A7, A9, M1, M14	Power	I/O Supply
FWSI_EN	B8	Input	Connect to V <sub>DD_IO</sub> through a 10k resistor
S <sub>DATA</sub>	B9	Input	SPI Slave In
V <sub>AA_PIX</sub>	B3, B12, M3, M12	Power	Pixel Supply
V <sub>DD</sub>	C1, F1, K1, B4, D5, G5, K5, D10, G10, K10, B11, C14, F14, J14	Power	Digital Supply
MONITOR_2	B5	Output	Monitor Output 2. If unused, do not connect.
MONITOR_1	B6	Output	Monitor Output 1. If unused, do not connect.
EXTCLK	B7	Input	External Clock Input
S <sub>DATAOUT</sub>	C8	Output	SPI Slave Out
TRIG_RD	C9	Input	Trigger Input for Readout Control. If unused, connect to ground.
DATA_0_N	C10	HiSPi	Differential Data Channel [0], Negative
DATA_0_P	C11	HiSPi	Differential Data Channel [0], Positive
DATA_2_N	C12	HiSPi	Differential Data Channel [2], Negative
DATA_2_P	C13	HiSPi	Differential Data Channel [2], Positive
DATA_3_P	D2	HiSPi	Differential Data Channel [3], Positive
DATA_3_N	D3	HiSPi	Differential Data Channel [3], Negative
DATA_1_P	D4	HiSPi	Differential Data Channel [1], Positive
DATA_1_N	D5	HiSPi	Differential Data Channel [1], Negative
MONITOR_0	C6	Output	Monitor Output 0. If unused, keep do not connect.
CS_N	C7	Input	SPI Chip Select (Active Low)
TRIG_INT	D9	Input	Trigger Input for Integration Control. If unused, connect to ground.
D_CLK_0_N	D11	HiSPi	Differential Clock [0], Negative
D_CLK_0_P	D12	HiSPi	Differential Clock [0], Positive
V <sub>DD_SLVS</sub>	D1, D14, G1, G14, K1, K14	Power	HiSPi Supply
D_CLK_1_P	P3	HiSPi	Differential Clock [1], Positive
D_CLK_1_N	P4	HiSPi	Differential Clock [1], Negative
RESET_N	D6	Input	Asynchronous Hard Reset (Active Low)
S <sub>CLK</sub>	D7	Input	SPI Clock Input
DATA_4_N	E10	HiSPi	Differential Data Channel [4], Negative
DATA_4_P	E11	HiSPi	Differential Data Channel [4], Positive
DATA_6_N	E12	HiSPi	Differential Data Channel [6], Negative
DATA_6_P	E13	HiSPi	Differential Data Channel [6], Positive

Table 5. PIN DESCRIPTIONS (163-PIN LGA PACKAGE)

Name	LGA Pin Name	Type	Description
DATA_7_P	E2	HiSPi	Differential Data Channel [7], Positive
DATA_7_N	E3	HiSPi	Differential Data Channel [7], Negative
DATA_5_P	E4	HiSPi	Differential Data Channel [5], Positive
DATA_5_N	E5	HiSPi	Differential Data Channel [5], Negative
DATA_8_N	F10	HiSPi	Differential Data Channel [8], Negative
DATA_8_P	F11	HiSPi	Differential Data Channel [8], Positive
DATA_10_N	F12	HiSPi	Differential Data Channel [10], Negative
DATA_10_P	F13	HiSPi	Differential Data Channel [10], Positive
DATA_11_P	F2	HiSPi	Differential Data Channel [11], Positive
DATA_11_N	F3	HiSPi	Differential Data Channel [11], Negative
DATA_9_P	F4	HiSPi	Differential Data Channel [9], Positive
DATA_9_N	F5	HiSPi	Differential Data Channel [9], Negative
D_CLK_2_N	G11	HiSPi	Differential Clock [2], Negative
D_CLK_2_P	G12	HiSPi	Differential Clock [2], Positive
D_CLK_3_P	H3	HiSPi	Differential Clock [3], Positive
D_CLK_3_N	H4	HiSPi	Differential Clock [3], Negative
DATA_12_N	H10	HiSPi	Differential Data Channel [12], Negative
DATA_12_P	H11	HiSPi	Differential Data Channel [12], Positive
DATA_14_N	H12	HiSPi	Differential Data Channel [14], Negative
DATA_14_P	H13	HiSPi	Differential Data Channel [14], Positive
DATA_15_P	H2	HiSPi	Differential Data Channel [15], Positive
DATA_15_N	H3	HiSPi	Differential Data Channel [15], Negative
DATA_13_P	H4	HiSPi	Differential Data Channel [13], Positive
DATA_13_N	H5	HiSPi	Differential Data Channel [13], Negative
VAA_PIX_A0	M8	Decoupling	External Noise Decoupling (0.1 $\mu$ F + 4.7 $\mu$ F to GND)
VAA_PIX_A1	M9	Decoupling	External Noise Decoupling (0.1 $\mu$ F + 4.7 $\mu$ F to GND)
VAA_PIX_A2	N8	Decoupling	External Noise Decoupling (0.1 $\mu$ F + 4.7 $\mu$ F to GND)
VAA_PIX_A3	P9	Decoupling	External Noise Decoupling (0.1 $\mu$ F + 4.7 $\mu$ F to GND)
VAA_PIX_A4	P10	Decoupling	External Noise Decoupling (0.1 $\mu$ F + 4.7 $\mu$ F to GND)
VAA_PIX_A5	P4	Decoupling	External Noise Decoupling (0.1 $\mu$ F + 4.7 $\mu$ F to GND)
VAA_PIX_B0	M6	Decoupling	External Noise Decoupling (0.1 $\mu$ F + 2.2 $\mu$ F to GND)
VAA_PIX_B1	M7	Decoupling	External Noise Decoupling (0.1 $\mu$ F + 2.2 $\mu$ F to GND)
VAA_PIX_B2	N6	Decoupling	External Noise Decoupling (0.1 $\mu$ F + 2.2 $\mu$ F to GND)
VAA_PIX_B3	N7	Decoupling	External Noise Decoupling (0.1 $\mu$ F + 2.2 $\mu$ F to GND)
VAA_PIX_B4	P5	Decoupling	External Noise Decoupling (0.1 $\mu$ F + 2.2 $\mu$ F to GND)
VAA_PIX_B5	P6	Decoupling	External Noise Decoupling (0.1 $\mu$ F + 2.2 $\mu$ F to GND)
VAA_PIX_C0	N9	Decoupling	External Noise Decoupling (0.1 $\mu$ F to GND)
VAA_PIX_C1	P11	Decoupling	External Noise Decoupling (0.1 $\mu$ F to GND)
VAA_PIX_BST	N5, N10	Power	Pixel Booster Supply

## SENSOR STATES

After Power-Up and while the RESET\_N pin is driven low, the image sensor enters a RESET state where all the configuration registers are initialized to their default state.

Once the RESET\_N pin is driven high the sensor will transition to the SLEEP state. While the sensor is in the SLEEP state, the registers can be programmed using the SPI interface. To exit the SLEEP state and enter STANDBY mode, the *reset\_register\_reg* (R0x3700) needs to be set to 0x001C. This register upload enables all analog blocks (including the on-chip PLL) and moves the sensor state to STANDBY.

When in STANDBY mode and upon user intervention the training patterns or IDLE words can be sent over the video interface allowing receiver locking. Once the host is ready to receive image data, the sensor's sequencer can be enabled. Depending on the configured operation mode, the sensor will either wait for user interaction or start grabbing images autonomously (CAPTURE). Disabling the sequencer moves the sensor state back to STANDBY. When disabling the PLL and analog blocks while in STANDBY state, the state machine will transition back to the SLEEP state. Asserting the RESET\_N pin forces the sensor to enter the RESET state, regardless of the current state.

The sensor state diagram is shown in Figure 11.

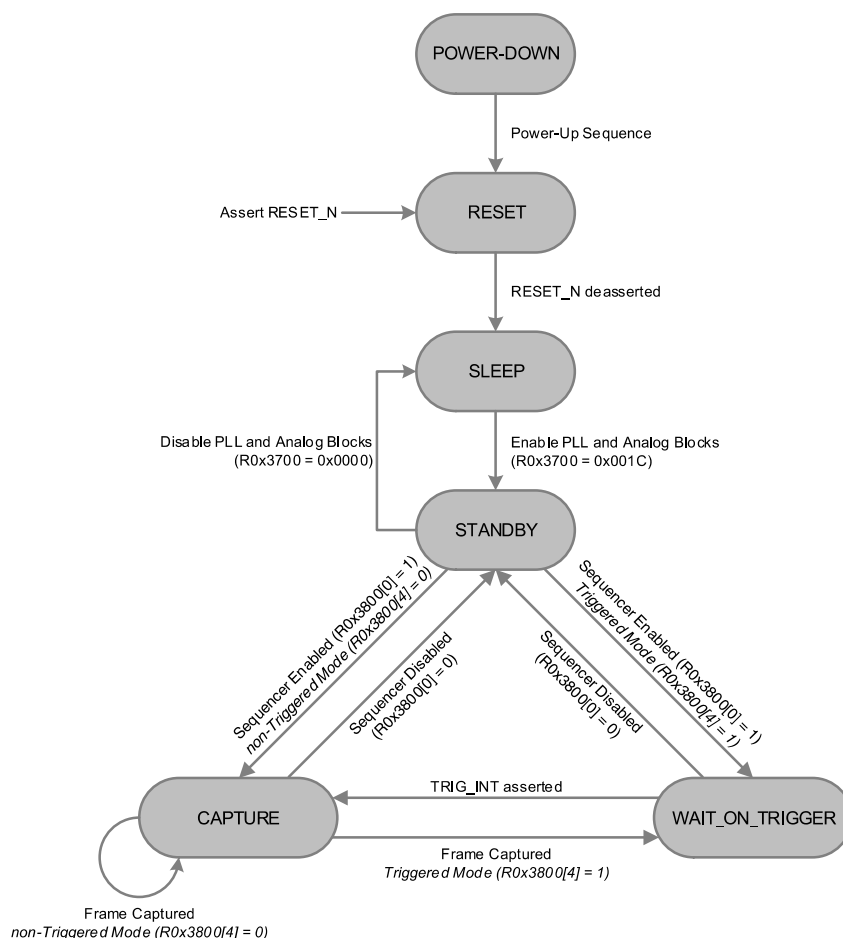


Figure 11. Sensor State Diagram

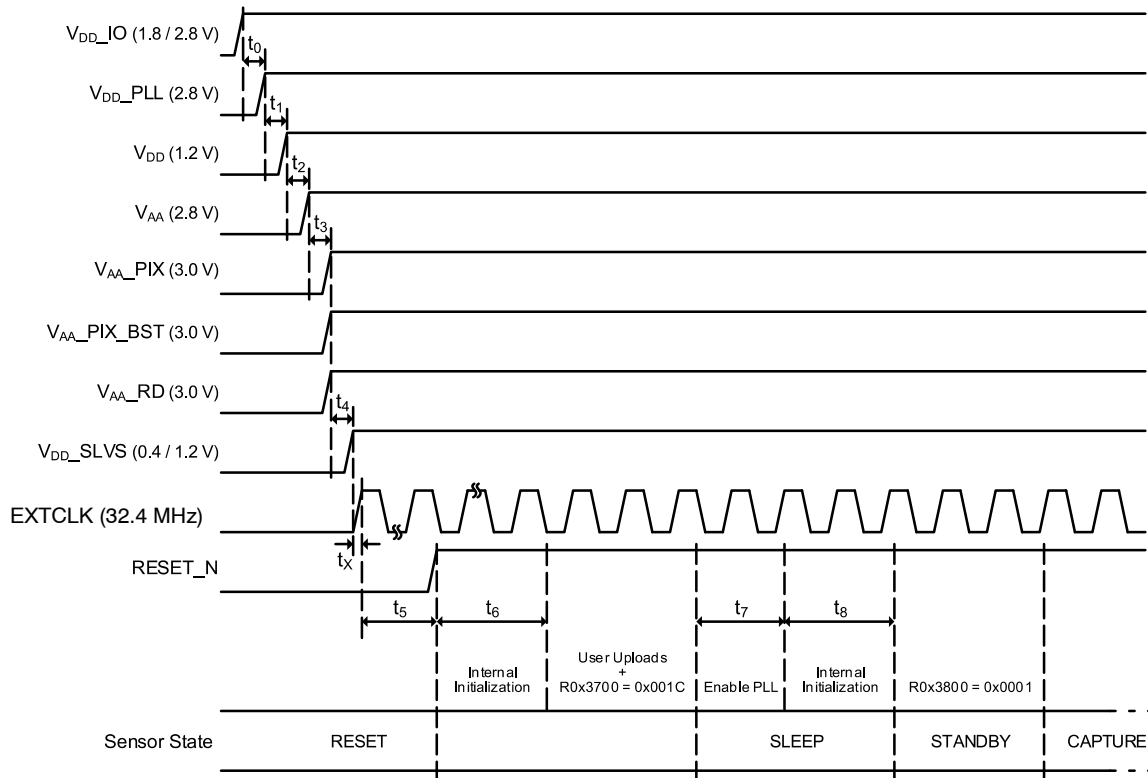
Table 6. TYPICAL TRANSITION TIMES

Sensor State	Transition Time	Description
POWER-DOWN	25 ms	Time required to transition from POWER-DOWN to CAPTURE state.
SLEEP	10 ms	Time required to transition from SLEEP to CAPTURE state.
STANDBY	< 16 line times	Time required to transition from STANDBY to CAPTURE state.
WAIT_ON_TRIGGER	2 line times + Synchronization Delay (< 50 ns)	Time required to transition from WAIT_ON_TRIGGER to CAPTURE (upon trigger action). A minimum delay of one line time will be added.

**POWER-UP AND POWER-DOWN SEQUENCE****POWER-UP SEQUENCE**

The recommended Power-Up sequence for the XGS sensor is shown in Figure 12. The available power supplies ( $V_{DD\_IO}$ ,  $V_{DD\_PLL}$ ,  $V_{DD}$ ,  $V_{AA}$ ,  $V_{AA\_PIX}$ ,  $V_{AA\_PIX\_BST}$ ,  $V_{AA\_RD}$  and  $V_{DD\_SLVS}$ ) must have the separation specified below.

1. Turn on  $V_{DD\_IO}$  power supply.
2. After 0–100  $\mu$ s, turn on  $V_{DD\_PLL}$  power supply.
3. After 0–100  $\mu$ s, turn on  $V_{DD}$  power supply.
4. After 0–100  $\mu$ s, turn on  $V_{AA}$  power supply.
5. Once  $V_{AA}$  is stable, power up  $V_{AA\_PIX}$ ,  $V_{AA\_PIX\_BST}$  and  $V_{AA\_RD}$ .
6. Once  $V_{AA\_PIX}$ ,  $V_{AA\_PIX\_BST}$  and  $V_{AA\_RD}$  are stable, power up  $V_{DD\_SLVS}$ .
7. After  $V_{DD\_SLVS}$  is stable, enable EXTCLK.
8. After EXTCLK has settled, hold RESET\_N low (active) for at least 30 EXTCLK cycles.
9. The sensor then loads the default register values from its on-chip memory. This takes approximately 1.5 ms after which the sensor is ready to accept user uploads (e.g. to configure a special mode).
10. Enable PLL and initialize sensor's internal analog blocks (*reset\_register\_reg* = 0x001C).
11. Once the analog blocks are initialized, the sensor transitions to STANDBY state and is ready to start image operations.
12. Enable the sequencer to transition to the CAPTURE state (*general\_config0\_reg[0]* = 1).



**Figure 12. Power-Up Sequence**

**Table 7. POWER-UP SEQUENCE**

Symbol	Definition	Min	Typ	Max	Unit
t <sub>0</sub>	V <sub>DD_IO</sub> to V <sub>DD_PLL</sub>	0 (Note 5)	100		μs
t <sub>1</sub>	V <sub>DD_PLL</sub> to V <sub>DD</sub>	0 (Note 5)	100		μs
t <sub>2</sub>	V <sub>DD</sub> to V <sub>AA</sub>	0 (Note 5)	100		μs
t <sub>3</sub>	V <sub>AA</sub> to V <sub>AA_PIX</sub> /V <sub>AA_PIX_BST</sub> /V <sub>AA_RD</sub>	0 (Note 5)	100		μs
t <sub>4</sub>	V <sub>AA_PIX</sub> /V <sub>AA_PIX_BST</sub> /V <sub>AA_RD</sub> to V <sub>DD_SLVS</sub>	0 (Note 5)	100		μs
t <sub>X</sub>	EXTCLK Settling Time	0.5	30 (Note 4)		ms
t <sub>5</sub>	Hard Reset	30			EXTCLK cycles
t <sub>6</sub>	Internal Initialization	1.5			ms
t <sub>7</sub>	PLL Lock Time	10	70		μs
t <sub>8</sub>	Internal Initialization		6.5		ms

4. The EXTCLK settling time is component-dependent.

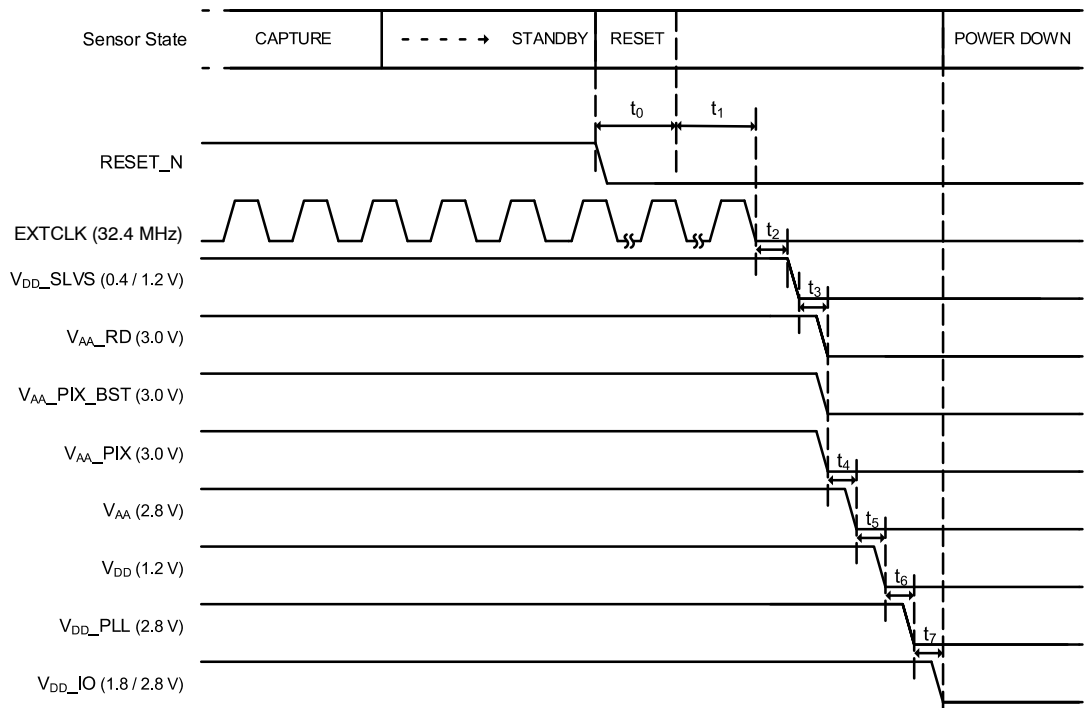
5. The minimum time does not include the settling time of the power supply.



**POWER-DOWN SEQUENCE**

The recommended Power-Down sequence for the XGS sensor is shown in Figure 13. The available power supplies must have the separation specified below.

1. Disable CAPTURE if output is active by disabling the sequencer (*general\_config0\_reg[0] = 0*).
2. Issue a sensor STANDBY request (*reset\_register\_reg[2] = 0*). By default, the transition to STANDBY state happens either after completion of current row (or frame) readout or instantly (configurable).
3. In STANDBY mode, activate reset by pulling down the RESET\_N line for at least 30 EXTCLKs.
4. EXTCLK can be stopped 0.5 ms after RESET\_N.
5. Turn off power supplies one by one. Wait at least until the supplies are stable before turning off the next supply. (reverse order of Power-Up Sequence).



**Figure 13. Power-Down Sequence**

**Table 8. POWER-DOWN SEQUENCE**

Symbol	Definition	Min	Typ	Max	Unit
$t_0$	Hard Reset	30			EXTCLK cycles
$t_1$	Reset to Disable EXTCLK	0.5			ms
$t_2$	$V_{AA\_RD} / V_{AA\_PIX\_BST} / V_{AA\_PIX}$ to $V_{AA}$	0 (Note 6)			$\mu$ s
$t_3$	$V_{DD\_SLVS}$ to $V_{AA\_RD} / V_{AA\_PIX\_BST} / V_{AA\_PIX}$	0 (Note 6)			$\mu$ s
$t_4$	$V_{AA\_RD} / V_{AA\_PIX\_BST} / V_{AA\_PIX}$ to $V_{AA}$	0 (Note 6)			$\mu$ s
$t_5$	$V_{AA}$ to $V_{DD}$	0 (Note 6)			$\mu$ s
$t_6$	$V_{DD}$ to $V_{DD\_PLL}$	0 (Note 6)			$\mu$ s
$t_7$	$V_{DD\_PLL}$ to $V_{DD\_IO}$	0 (Note 6)			$\mu$ s

6. The minimum time does not include the settling time of the power supply.

## INTEGRATION MODES

In a global shutter sensor, light integration takes place on all pixels in parallel, although subsequent readout is sequential. Figure 14 shows the integration and readout sequence for the global shutter. All pixels are light sensitive during the same period of time.

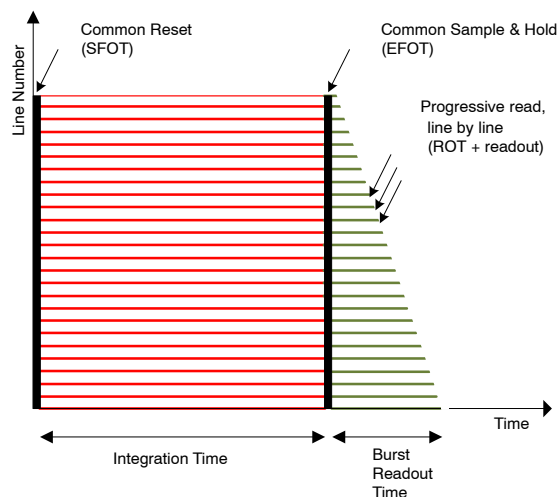


Figure 14. Global Shutter Operation

The whole pixel core is reset simultaneously and after the integration time all pixel values are sampled at the same time on the storage node inside each pixel. The pixel core is read out line by line after integration. Note that Figure 14 shows a configuration where integration and readout operations are not pipelined. In a pipelined configuration, integration and readout are performed simultaneously.

### Pipelined Global Shutter Mode

In pipelined shutter mode, the integration and readout are active concurrently. Images are continuously read and integration of frame N is ongoing during readout of the previous frame N-1. The readout of every frame starts with a Frame Overhead time (EFOT), during which the analog value on the pixel diode is transferred to the pixel memory element. After the Frame Overhead Time, the sensor is read out line per line. Image array operations and readout are pipelined. The image array operations are performed in the Row Overhead Time (ROT). During the ROT sequence, an image row is selected for readout.

At the start of the integration the sequencer schedules another global operation on the pixel array. This sequence is referred to as Start of integration frame overhead sequence (SFOT). During this SFOT, the readout shall be halted temporarily.

## MASTER MODE (NON-TRIGGERED)

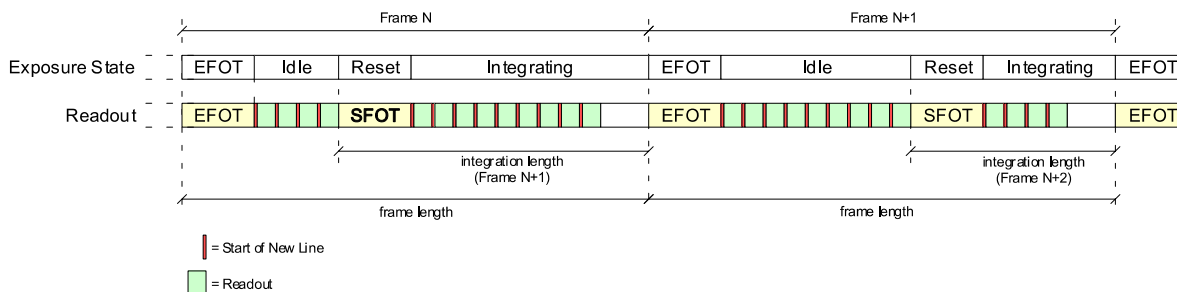


Figure 15. Master Mode (non-Triggered)

In this operation mode, the integration time is set through the register interface and the sensor integrates and reads out the images autonomously. The sensor acquires images without any user interaction as shown in Figure 15.

On a high level, the frame time consists of a non-integrating time and integration time (during which the pixels are light sensitive and integrating light). The sum of both parameters is the frame time, which is configured in multiple of line periods. Within this total frame time, the

Sequencer schedules the frame operations required to initiate and terminate the light integration. The integration period is started with a Start-of-Integration FOT (SFOT) sequence and is ended with an End-of-Integration FOT (EFOT) sequence. Note that both SFOT and EFOT operations take some time during which the readout will be halted. This will be reflected in an idle period on the sensor's interface. The parameters defining the frame and integration properties are listed in Table 9 below.

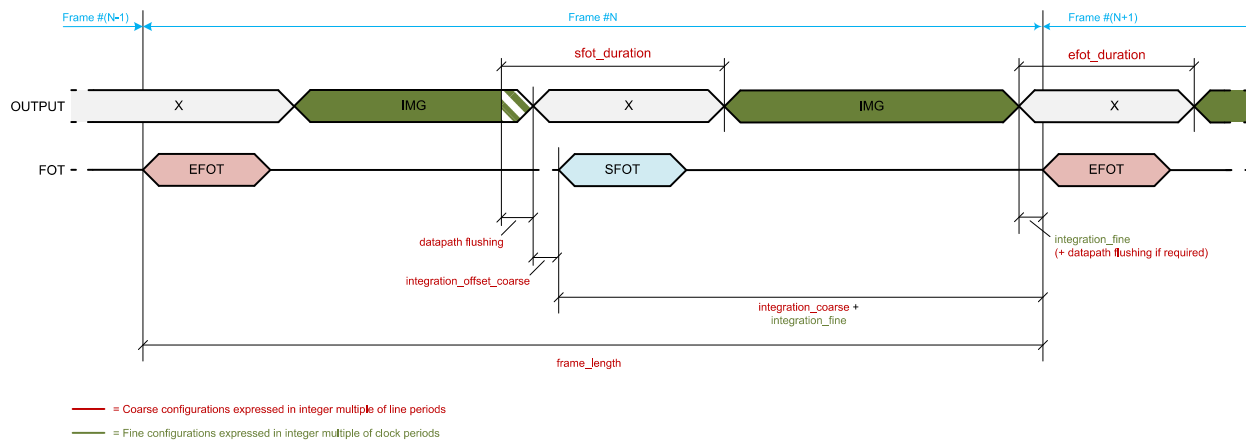
**Table 9. INTEGRATION AND FRAME TIMING PARAMETERS**

Name	Description
line_time	Duration of one line, expressed in logic clock cycles. The minimum line time shall be dictated by the A/D conversion time and readout time (whichever is larger).
frame_length	Defines the total frame time as $\text{frame\_length} * \text{line\_time}$ logic clock periods. This parameter needs to be configured large enough such that both the integration control operations (i.e. SFOT, EFOT and configured integration time) and the readout operations (ROI readout + black lines) can happen.
integration_coarse	Defines the coarse part of the integration time. Total integration time in logic clock periods is $\text{integration\_coarse} * \text{line\_time} + \text{integration\_fine}$
integration_fine	Defines the fine part of the integration time. Total integration time in logic clock periods is $\text{integration\_coarse} * \text{line\_time} + \text{integration\_fine}$
integration_offset_coarse	Offset between the Sequencer induced SFOT period and the start of the SFOT, expressed in line periods. The total integration offset time, expressed in logic clock cycles, is defined as $(\text{integration\_offset\_coarse} + \text{overhead}) * \text{line\_time}$ . This parameter allows to increase the latency between a trigger event and the effective start of integration in triggered modes.

The frame parameters and their relations are depicted in Figure 16 below. Note that the green area depicts the readout of regular lines (black reference / ROI defined image lines), while the grey area represents the access to dummy lines (no image data). The shaded green part represents the line

periods during which the control and datapath pipeline is flushed.

Minimum integration time limitations are listed in Table 10.

**Figure 16. Frame Timing and Exposure Parameters**

## MASTER MODE (TRIGGERED)

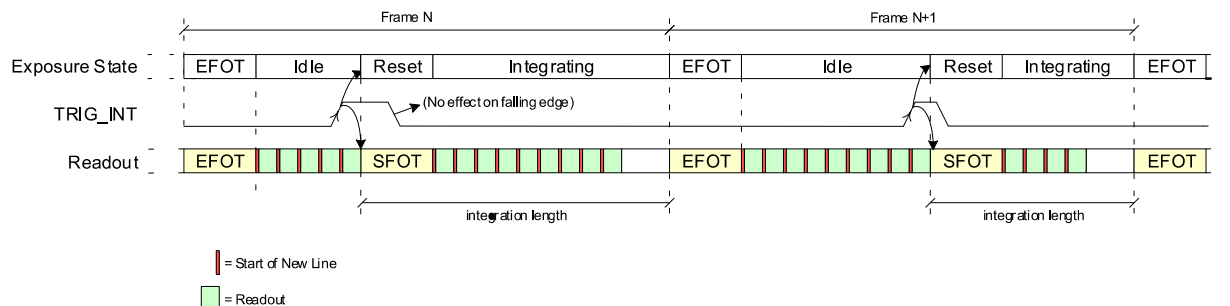


Figure 17. Master Mode (Triggered)

In Triggered Master Mode, a rising edge on the TRIG\_INT pin is used to trigger the start of integration as shown in Figure 17. The integration time is defined by register configuration (*integration\_coarse*, *integration\_fine*). The sensor shall autonomously integrate during this predefined time, after which the EFOT operation starts and the image array is read out sequentially. A falling

edge on the synchronization pin does not have any impact on the readout or integration and subsequent frames are started again for each rising edge.

Figure 18 below shows the pipelined operation in triggered master mode (i.e. trigger assertion during frame readout).

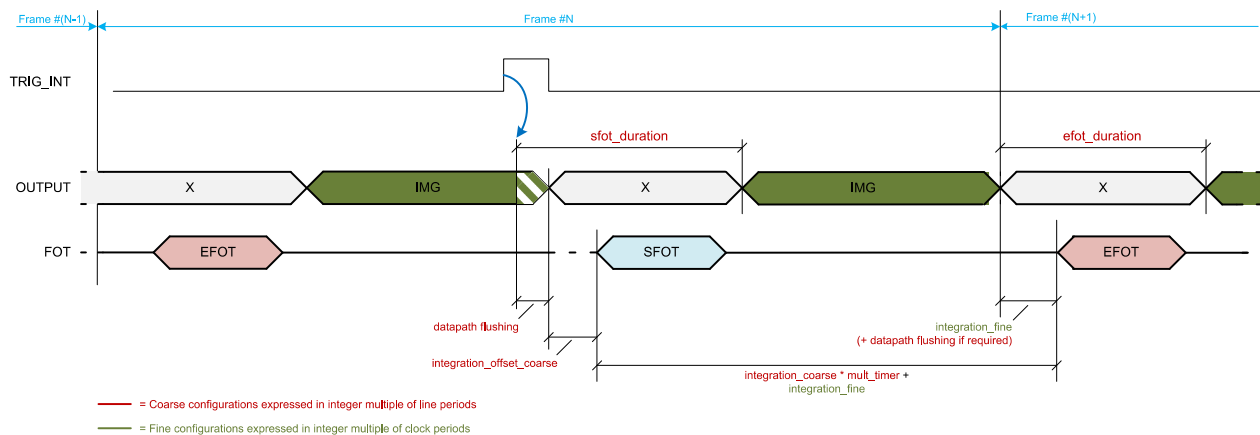


Figure 18. Integration Control in Triggered Master Mode

Note that each trigger reads out only one image.

The latency between a trigger event and the start of the SFOT operation is constant and predictable. It is defined by the coarse offset configuration + overhead.

### NOTES:

- The trigger is an asynchronous signal which is synchronized in the SCU. As a consequence, synchronization jitter can be observed.
- The polarity of the TRIG\_INT pin is controlled by *trig\_int\_polarity*. The operation described above corresponds to *trig\_int\_polarity* = '0'.

- The response time between a rising edge of TRIG\_INT and the start of integration is fixed, besides the synchronization uncertainty and jitter.

The following registers are not used in this mode and here no influence (implicitly defined by the trigger):

- *integration\_offset\_fine*,
- *frame\_length*

Minimum integration time limitations are listed in Table 10.

## SLAVE MODE (TRIGGERED)

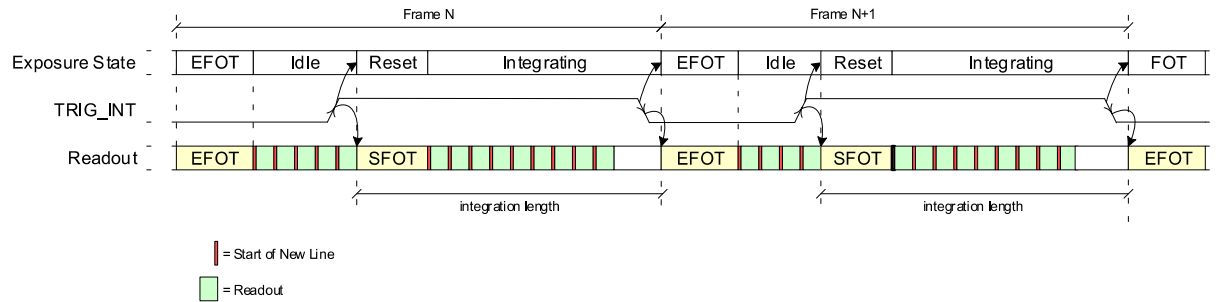


Figure 19. Slave Mode (Triggered)

The slave mode depicted in Figure 19 adds more manual control to the sensor. The integration time registers (*frame\_length* and *integration*) are ignored in this mode and the integration time is rather controlled by an external pin.

As soon as the control pin is asserted, the Sequencer schedules the SFOT operations. The integration continues until the external pin is deasserted by the user/system. Now, the image is sampled and the readout is initiated.

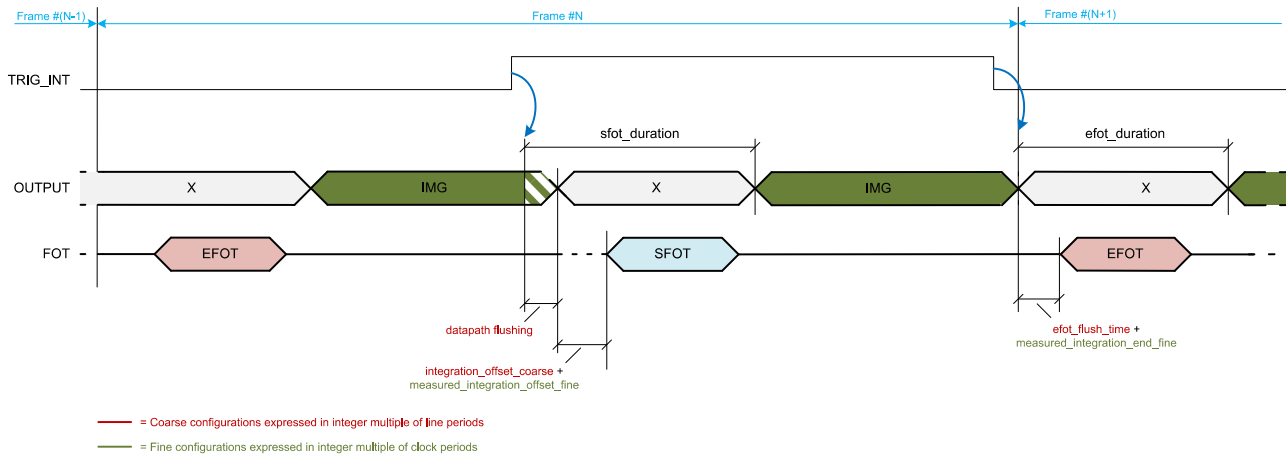


Figure 20. Integration Control in Slave Mode (Triggered)

The latency between the trigger events and the SFOT/EFOT operations respectively is fixed and predictable. The latency between a trigger assertion and the SFOT operation is controlled through *integration\_offset\_coarse*.

## NOTES:

- The trigger is an asynchronous signal which is synchronized in the Sequencer. As a consequence, synchronization jitter can be observed.
- The response time between a TRIG\_INT event and the start/end of integration shall be constant, besides the synchronization uncertainty and jitter.

- The following registers are not used in this mode and do not have any influence (implicitly defined by the trigger):

- ♦ *integration\_coarse*,
- ♦ *integration\_fine*,
- ♦ *frame\_length*

Minimum integration time limitations are listed in Table 10 below.

Table 10. MINIMUM INTEGRATION TIME LIMITATIONS (Note 7)

Number of Output Lanes	Minimum Integration Time (in $\mu$ s)	
	Non-Triggered	Triggered
4	TBD	TBD
8	TBD	TBD
16	TBD	TBD

7. The minimum integration time depends on the configured line time. The values in this table assume the minimum recommended line time is used.

### Readout Modes

By default, the readout of the pixel array does not require any user interaction. The sequencer initiates the readout as soon as integration ends and the entire readout is done autonomously. This is the default readout mode.

Optionally, the frame readout can be controlled externally. This requires configuring the TRIG\_RD input as a frame or line trigger. Table 11 below lists the parameters that control the triggered readout operation.

Table 11. TRIGGERED READOUT PARAMETERS

Register Name	Description
frame_trigger_en	Start the frame readout upon assertion of TRIG_RD when enabled. This configuration has priority over line_trigger_en.
frame_trigger_mode	Only valid for frame triggered readout modes. '0': Regular frame triggered mode: The sensor starts the readout of one frame upon a rising trigger edge '1': The sequencer continues frame grabbing as long as the trigger is asserted.
line_trigger_en	Start the readout of one line upon assertion of TRIG_RD when enabled. Only one line is read out for each trigger assertion.

Note that *contexts\_reg.frames* determines how many frames can be read out. This implies that the sequencer will not accept any new trigger once the number of

*contexts\_reg.frames* have been read out. If this is not desired, frames should be configured to 0.

### FRAME TRIGGERED READOUT

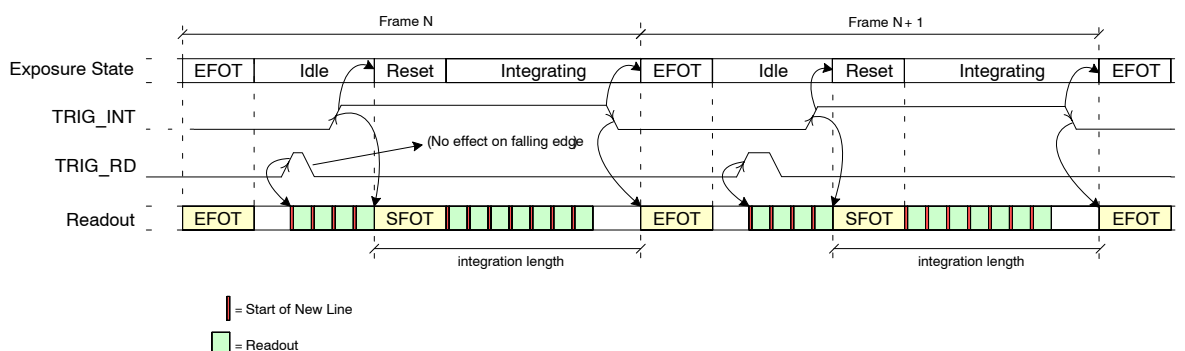


Figure 21. Frame Triggered Readout Mode

XGS 12000 supports two frame triggered readout options, configurable in the *frame\_trigger\_mode* register (refer to Table 11).

*frame\_trigger\_mode* = 0

In a global shutter mode, the integration is ended by the EFOT. In a non-triggered readout mode, the readout is initiated automatically after the EFOT operations. In frame triggered mode, the Sequencer will not start the readout, but

instead it waits until the frame-trigger gets asserted. Once an event (rising or falling depending on the configured polarity) is detected the readout starts and the image is read out line after line.

Note that the trigger assertion is latched and served at the first coming internal new line reference (internal time base). As a consequence one may observe a trigger latency up to a line time.

Frame triggered readout can be combined with triggered integration modes.

*frame\_trigger\_mode = 1*

In this mode, the trigger acts as an external sequencer enable signal. An event (rising or falling depending on the configured polarity) starts the frame readout. After this first frame, the sequencer continues running, cycling through the active contexts, if more than one context is enabled. The end condition depends on the value given in *contexts\_reg.frames*:

- *contexts\_reg.frames > 0*: The Sequencer continues running and reads out the given amount of frames, after which it returns to the WAIT\_ON\_TRIGGER state. After the readout, the sequencer is waiting for another trigger, after which a new sequence is initiated. Note that a new batch of frames shall be read out in case the trigger is asserted at the end of the previous batch.

- *contexts\_reg.frames = 0*: The Sequencer continues running as long as the TRIG\_RD is asserted. Once the trigger is deasserted, the Sequencer returns to the WAIT\_ON\_TRIGGER state, in which it is ready to accept a new trigger event.

Note that this mode is available for both triggered and non-triggered global shutter modes and it can be combined with the use of multiple contexts. When using multiple contexts it is also possible to configure the number of desired frames per context. The sequencer cycles through the active contexts and generates as many frames as configured per context. When retriggered, the sequencer reinitializes the frame properties and starts the readout from a fresh state (i.e. does not continue from where it ended in the previous batch).

## LINE TRIGGERED READOUT

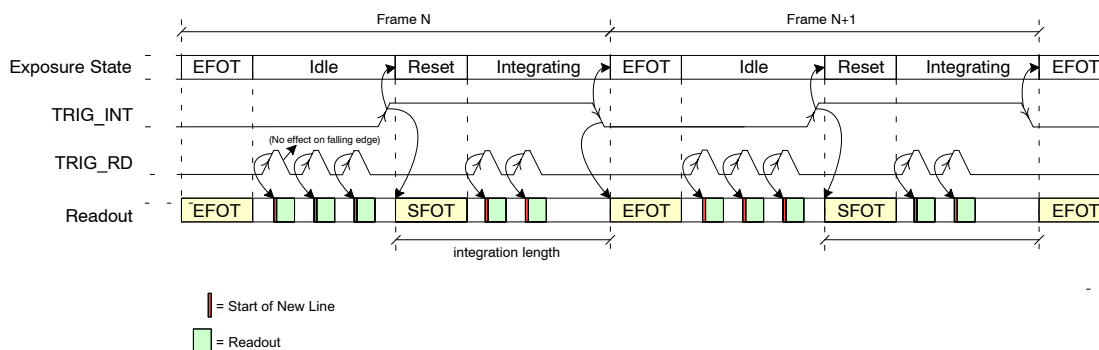


Figure 22. Line Triggered Readout

The line triggered readout mode is enabled when *line\_trigger\_en* is asserted and *frame\_trigger\_en* is deasserted. The line triggered readout mode is comparable to frame triggered readout, but in this mode only one line is read out for each trigger. Note that a trigger is latched and interpreted during the following line period if the sensor is retriggered during readout.

Line triggered readout is to be used in conjunction with triggered integration modes.

## Features Overview

The XGS family has a wide array of features to enhance functionality or to increase versatility. A summary of features follows.

### RESET

The RESET\_N input (pin F8) is an active low control input for asynchronous hard reset. During the power-up period, RESET\_N must be asserted, then must be deasserted after the power supplies are settled. The minimum RESET\_N assert time is 30 EXTCLK cycles.

## MONITOR OUTPUTS

The XGS sequencer provides three monitor outputs (pins E8, D8 and D7) which can be used to monitor the internal states of the sequencer. The monitor signals can be configured separately for each monitor output.

## CONTEXT SWITCHING

XGS supports up to three contexts which allow the user to program a number of configurations and let the sensor cycle through these. Switching from one context to another is done at the start of a frame and cannot corrupt the ongoing readout. The registers that control the switching are grouped in the *contexts\_reg*. The active context switching can be done manually by changing the value in the *active\_contexts* register or the sequencer can take control. If programmed, the sequencer will cycle through two or three contexts sequentially as depicted in Figures 23 and 24.

- Two Context Switching  
(*context\_reg.active\_contexts = 0x3*)  
context 0 → context 1 → context 0...

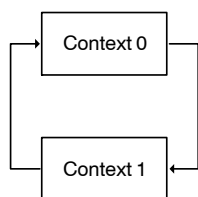


Figure 23. Two Context Switching

- Three Context Switching  
(*context\_reg.active\_contexts* = 0x7)  
context 0 → context 1 → context 2 → context 0...

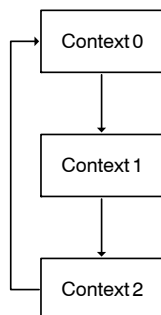


Figure 24. Three Context Switching

- Multiple Frame Context Switching  
In addition to defining up to three contexts, the number of frames per context can be configured for each context separately. In the example configuration depicted in Figure 25, the sensor first generates three frames using *context 0* settings followed by a single *context 1* frame and two *context 2* frames. The sensor loops through this sequence until the sequencer is disabled. The number of frames per context switch is configured in *contexts\_reg.frames\_ctxt0* (for context0).  
3 x context 0 → context 1 → 2 x context 2  
→ 3 x context 0...

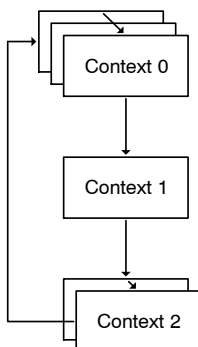


Figure 25. Multiple Frame Context Switching

## TEST PATTERN

The XGS sensor has the capability of injecting a number of test patterns into the datapath. As the test pattern generator is placed at the beginning of the digital datapath,

it can be used to check the functions of the digital blocks or to test the frame grabber or receiver operation. The test patterns can be configured in the *test\_pattern\_mode\_reg.test\_pattern\_mode* and only one pattern can be activated at a given point in time.

## DATA PEDESTAL

The data pedestal is a constant offset that is added to the pixel values at the end of the datapath. The pedestal or offset value can be configured separately for each color channel (*G<sub>R</sub>*, *G<sub>B</sub>*, *R* and *B*) and for each context. The offset is a 12-bit value.

## GAIN STAGES

### Analog Gain

A column-based analog gain of 1x, 2x or 4x can be applied to the output signal.

### Digital Gain

As opposed to the analog gain stage, the digital gain can be configured to separate levels for each color channel (*G<sub>R</sub>*, *G<sub>B</sub>*, *R* and *B*). The digital gain factor ranges from 1/32 to 2 in steps of 1/32 (64 steps) and its configuration can be represented by the equation below:

$$\text{Digital gain} = \text{Dg\_factor} / 2^5 \quad (\text{eq. 1})$$

## COMPANDING MODE

The companding mode can be used to compress 12-bit pixel data into 10-bit values. The line time remains the time required to convert a 12-bit ADC sample; gain is only achieved when, due to lane multiplexing, the system becomes I/O limited. In that situation, being able to send out 12-bit pixels using only 10 bits, can be useful to boost the frame rate. When companding mode is enabled, the precision of the digital output is 1 Least Significant Bit (LSB) in the low light area, but towards the upper region, the granularity gradually increases to 2, 4, and 8 LSBs as shown in Figure 26. In all cases the ADC quantization steps will be less than the photon shot noise performance of the pixel.

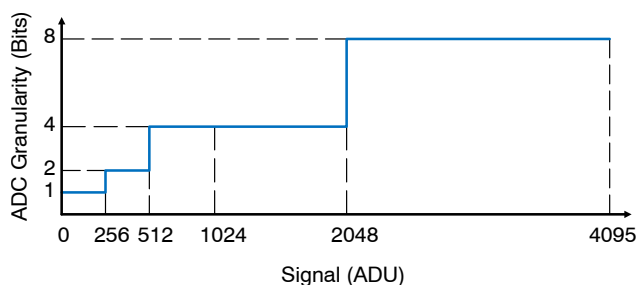


Figure 26. ADC Granularity – Companding Mode

## FRAME RATE

Assuming the readout of a frame takes longer than the integration, the frame rate can be influenced by changing one or more of the following parameters:



- Vertical resolution (number of lines in ROI)
- Number of data output lanes (16 / 12 / 8 / 4 or mux mode (4:4 / 4:3 / 4:2 / 4:1))

The frame rate scales linearly with the number of lines (vertical direction) but not with the number of columns (horizontal direction) due to the column ADC architecture. Using the sensor with a reduced number of data lanes will lower the frame rate.

Alternatively, the frame time can be configured through *line\_time* and *frame\_time*. The line time should be large enough in order to process a full line and the frame time should be configured such that at least all ROIs can be read out and that the maximum integration can be scheduled in. When one of the two conditions are violated the sensor gives either priority to the readout or the integration (*int\_priority*).

### Lane Multiplexing

The lane multiplexing function can be used to reduce the number of output data lanes and thus the output data rate.

This can be useful in case the receiver cannot accept all 16 data lanes or the backend is unable to process the sensor's full data rate. The sensor has one multiplexer for each PHY; six in total. Each multiplexer connects 4 datapath outputs to one PHY and can be configured to distribute the data from the 4 datapath inputs over either 1, 2, 3 or 4 outputs; i.e. the sensor supports 4 multiplexing schemes:

- 4:4 multiplexing: no multiplexing; each datapath lane is connected to a HiSPi lane (total of 16 lanes).
- 4:3 multiplexing: four datapath lanes are multiplexed to three HiSPi lanes (total of 12 lanes).
- 4:2 multiplexing: four datapath lanes are multiplexed to two HiSPi lanes (total of 8 lanes).
- 4:1 multiplexing: four datapath lanes are multiplexed to a single HiSPi lane (total of 4 lanes).

The four different multiplexing schemes are illustrated in Figures 27 to 30. The pixel readout order for each multiplexing mode is depicted in Figures 31 to 34.

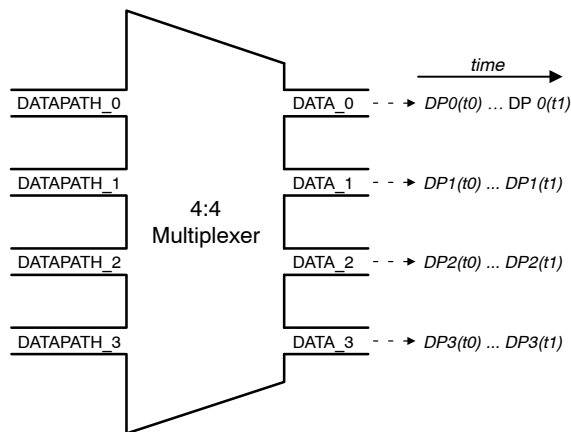


Figure 27. 4:4 Multiplexing (16 Lanes)

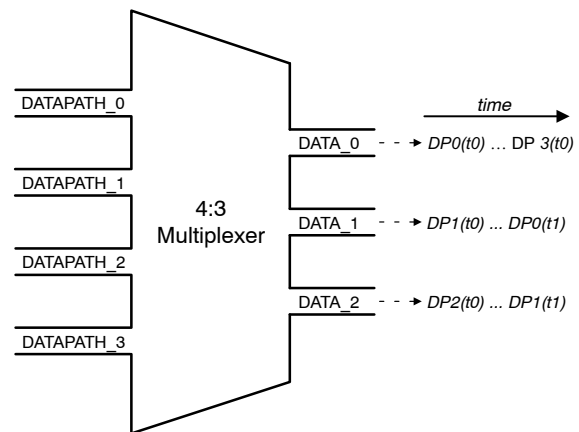


Figure 28. 4:3 Multiplexing (12 Lanes)

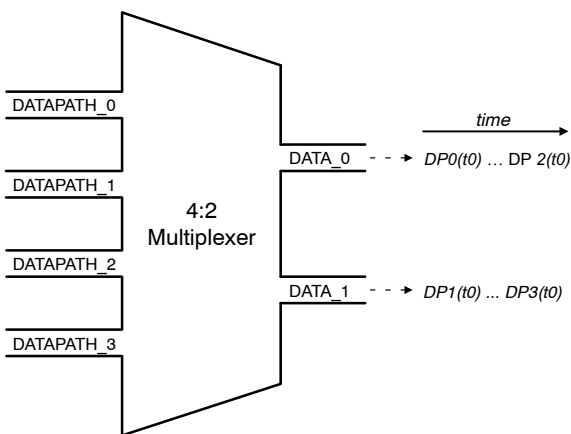


Figure 29. 4:2 Multiplexing (8 Lanes)

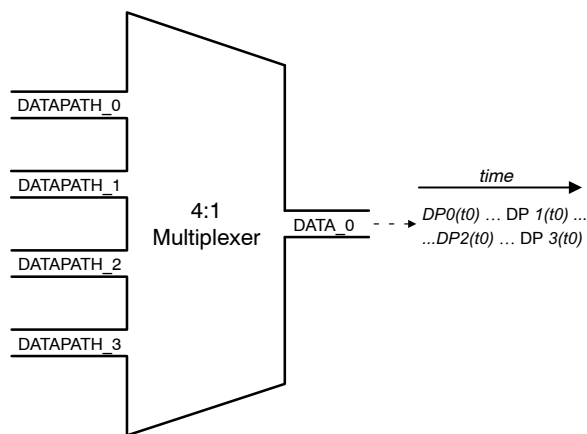


Figure 30. 4:1 Multiplexing (4 Lanes)

Table 13 lists the active data lanes in function of the multiplexing scheme. As depicted in Table 13, HiSPi lane 0

is the lane that is always active, regardless of the selected multiplex scheme.

**Table 12. ACTIVE DATA LANES IN PHY0 IN FUNCTION OF MUX MODE**

Mux Mode	Lane_0	Lane_2	Lane_4	Lane_6
4:4	X	X	X	X
4:3	X	X	X	
4:2	X	X		
4:1	X			

NOTE: Lane usage is illustrated using the first four lanes only (i.e. for a single PHY).

The data output on each lane within a single PHY, depending on the multiplexing scheme, is represented in

Figures 31 to 34. The numbers in the squares represent the actual column address in the pixel array.

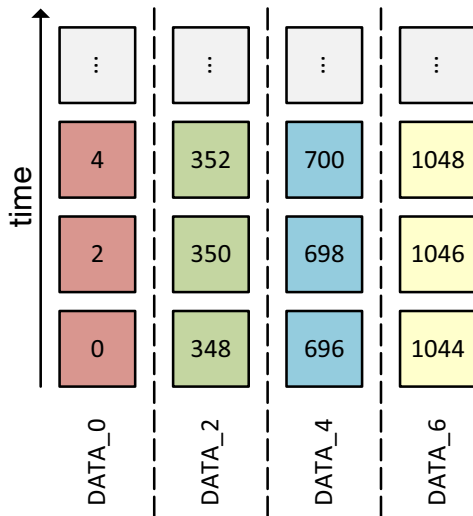


Figure 31. Column Output with 4:4 Multiplexing

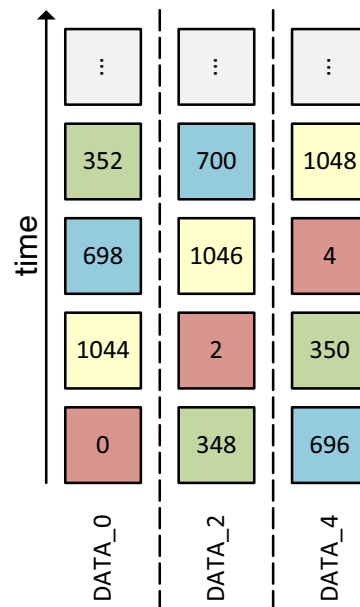


Figure 32. Column Output with 4:3 Multiplexing

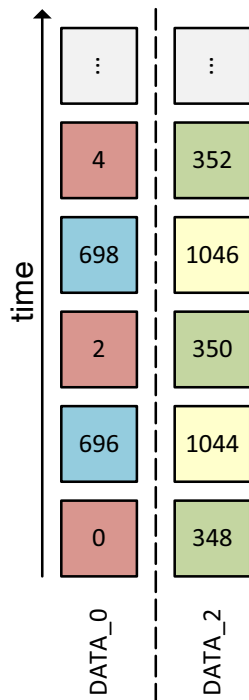


Figure 33. Column Output with 4:2 Multiplexing

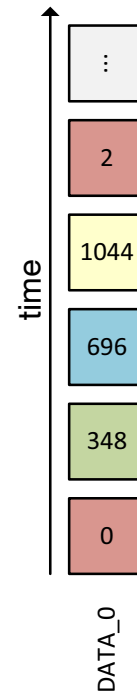


Figure 34. Column Output with 4:1 Multiplexing

Figure 35 shows on which output lane columns are sent in case a row with an even address is read and the sensor is configured to have  $G_R$  and  $G_B$  pixels sent out on top (even

numbered lanes) and R and B pixels to the bottom (odd numbered lanes). Figure 36 shows the column output in case a row with an odd address is read.

EVEN ROW	DATA_0 (G <sub>R</sub> )	SYNC	SOF	1, 3, 5... 345, 347	EOL	BLANK
	DATA_1 (R)	SYNC	SOF	0, 2, 4... 344, 346	EOL	BLANK
	DATA_2 (G <sub>R</sub> )	SYNC	SOF	349, 351, 353... 693, 695	EOL	BLANK
	DATA_3 (R)	SYNC	SOF	348, 350, 352... 692, 694	EOL	BLANK
	⋮	⋮	⋮	⋮	⋮	⋮
	DATA_14 (G <sub>R</sub> )	SYNC	SOF	... 2781, 2783	EOL	BLANK
	DATA_15 (R)	SYNC	SOF	... 2780, 2782	EOL	BLANK

Figure 35. Column Output Sequence (Even Row Address)

ODD ROW	DATA_0 (G <sub>B</sub> )	SYNC	SOF	0, 2, 4... 344, 346	EOL	BLANK
	DATA_1 (B)	SYNC	SOF	1, 3, 5... 345, 347	EOL	BLANK
	DATA_2 (G <sub>B</sub> )	SYNC	SOF	348, 350, 352... 692, 694	EOL	BLANK
	DATA_3 (B)	SYNC	SOF	349, 351, 353... 693, 695	EOL	BLANK
	⋮	⋮	⋮	⋮	⋮	⋮
	DATA_14 (G <sub>B</sub> )	SYNC	SOF	... 2780, 2782	EOL	BLANK
	DATA_15 (B)	SYNC	SOF	... 2781, 2783	EOL	BLANK

Figure 36. Column Output Sequence (Odd Row Address)

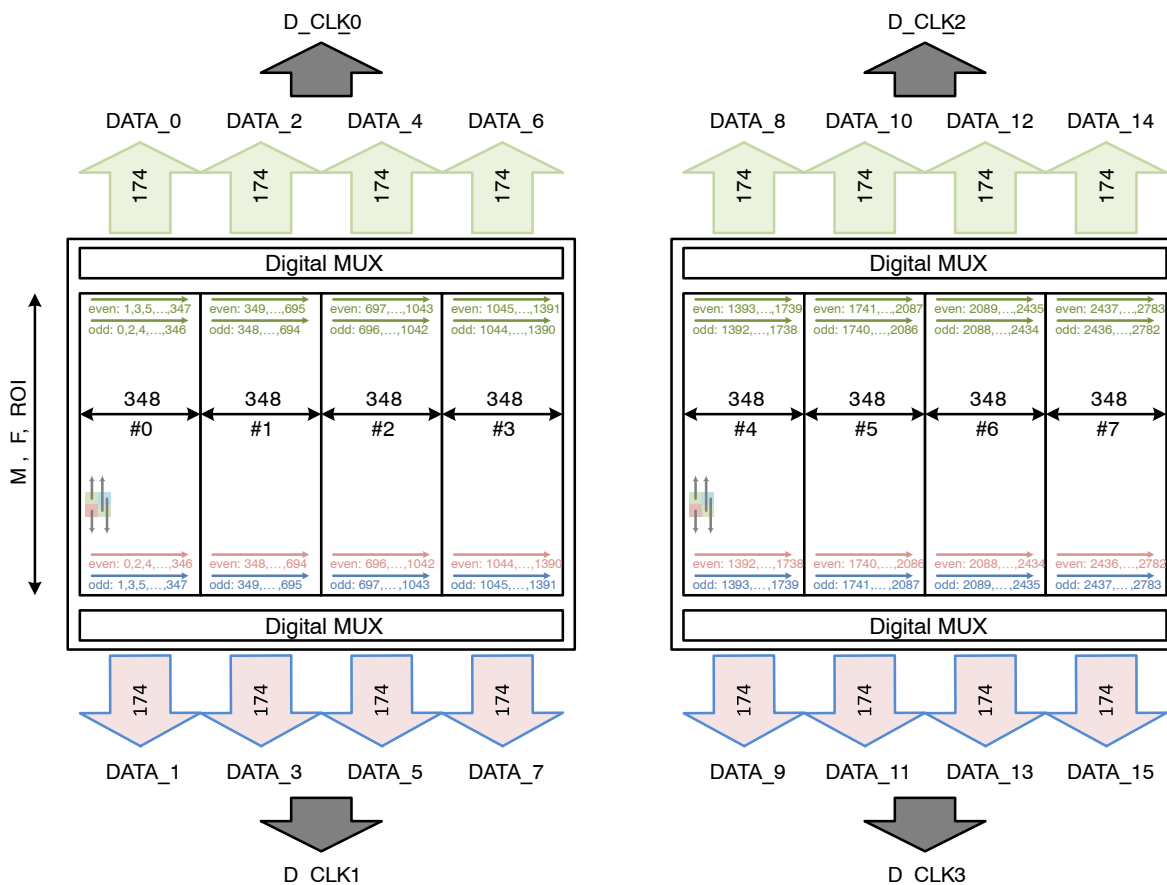


Figure 37. Pixel Readout Order (16 Lanes)

**SERIAL PERIPHERAL INTERFACE**

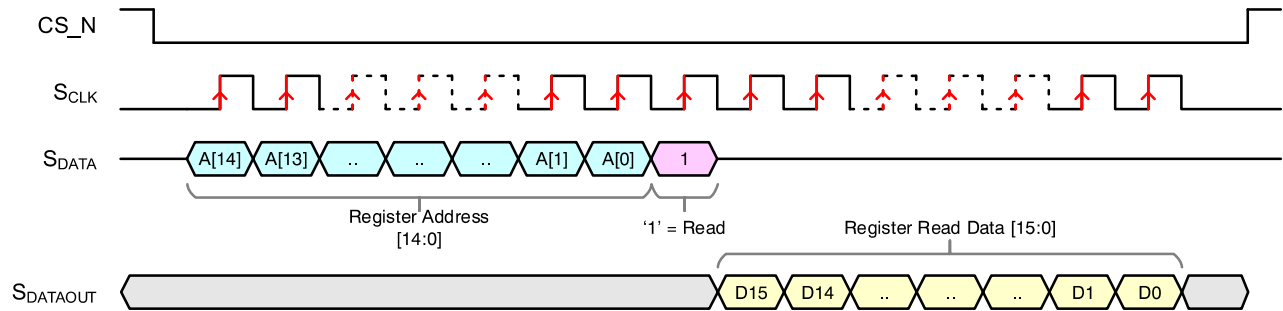
The sensor's configuration registers are accessible through a Serial Peripheral Interface (SPI). The SPI is a full-duplex, synchronous interface and uses four wires:

- CS\_N: Chip Select (*active low*)
- SCLK: Serial Input Clock
- S<sub>DATA</sub>: Serial Data Input
- S<sub>DATAOUT</sub>: Serial Data Output

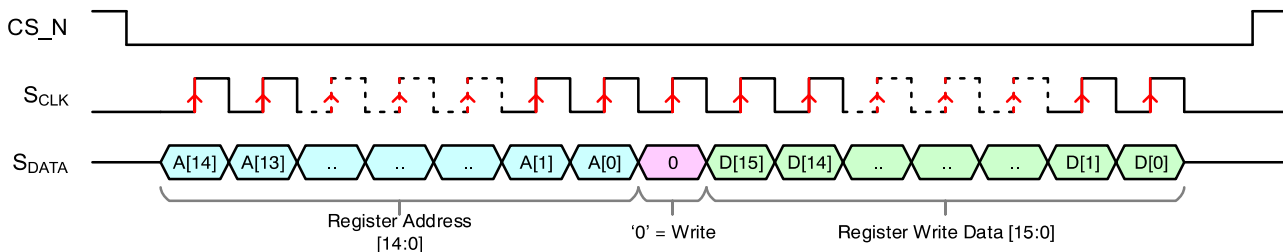
The SPI interface uses a master-slave setup in which the sensor is the slave. Every read or write access is initiated by the master by pulling down the CS\_N line. The master then sends a 15-bit register address followed by a single

read/write bit. If the read/write bit is set to 1, the slave *reads* the 16-bit data stored at the specified register address and returns it to the master over the S<sub>DATAOUT</sub> line. A single SPI read operation is shown in Figure 38. In case the read/write bit is set to '0', the master sends another 16 bits of data for the slave to *write* to the previously specified register address. A single SPI write transaction is depicted in Figure 39.

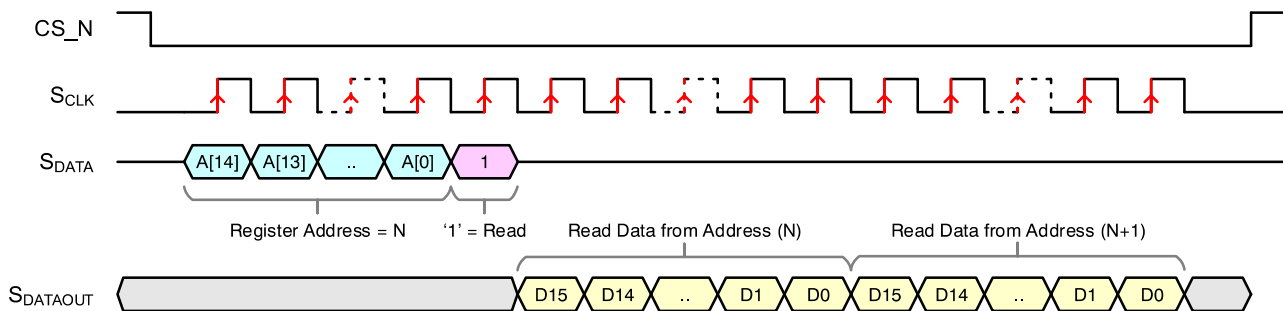
Both address and register data is sent serially and synchronous to the SCLK. A single SPI transaction consists of 32 bits. In order to speed up the SPI communication, a 32 sequential read and write is possible. The sequential register access is illustrated in Figure 40 and 41.



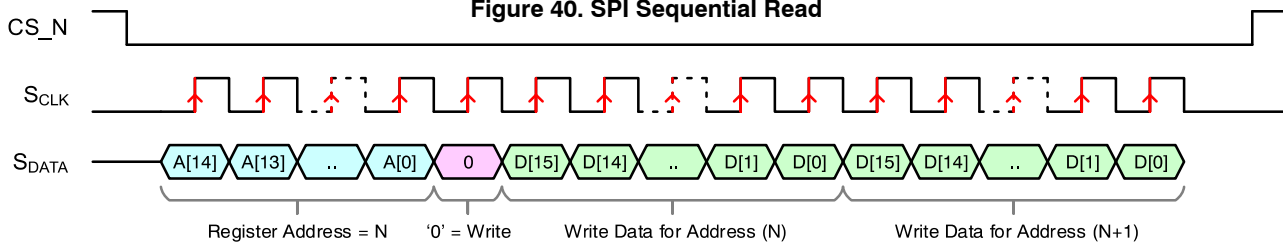
**Figure 38. Single SPI Read**



**Figure 39. SPI Single Write**



**Figure 40. SPI Sequential Read**



**Figure 41. SPI Sequential Write**

## ELECTRICAL SPECIFICATIONS

Unless stated otherwise, the following specifications apply to the following conditions:

$$V_{AA\_PIX} = V_{AA\_PIX\_BST} = V_{AA\_RD} = 3.0 \text{ V};$$

$$V_{AA} = V_{DD\_PLL} = 2.8 \text{ V};$$

$$V_{DD\_IO} = 1.8 \text{ V};$$

$$V_{DD} = 1.2 \text{ V};$$

$$V_{DD\_SLVS} = 1.2 \text{ V};$$

$$\text{EXTCLK} = 32.4 \text{ MHz};$$

$$T_J = 25^\circ\text{C};$$

### Serial Peripheral Interface (SPI)

The electrical characteristics of the four-wire serial interface ( $\text{CS\_N}$ ,  $\text{SCLK}$ ,  $\text{SDATA}$  and  $\text{SDATAOUT}$ ) are shown in Figures 42, 43 and 47. The timing parameters are listed in Table 13.

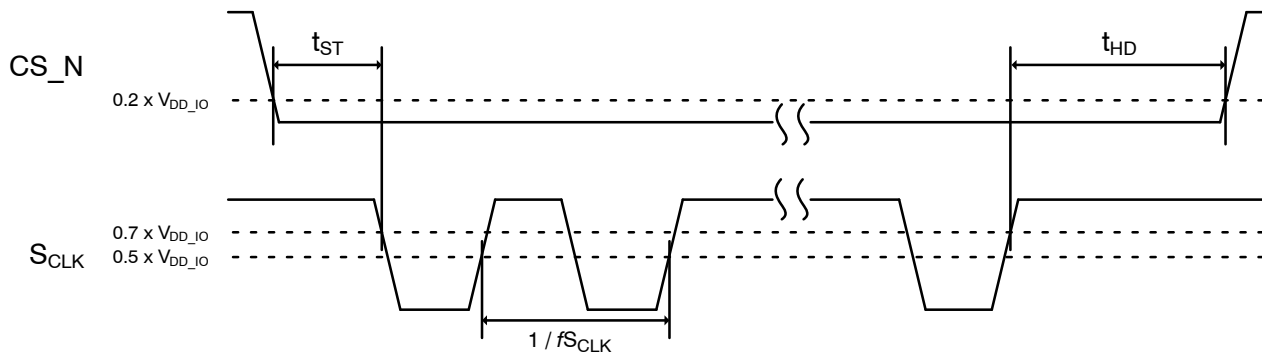


Figure 42. SPI Timing Diagram – Chip Select

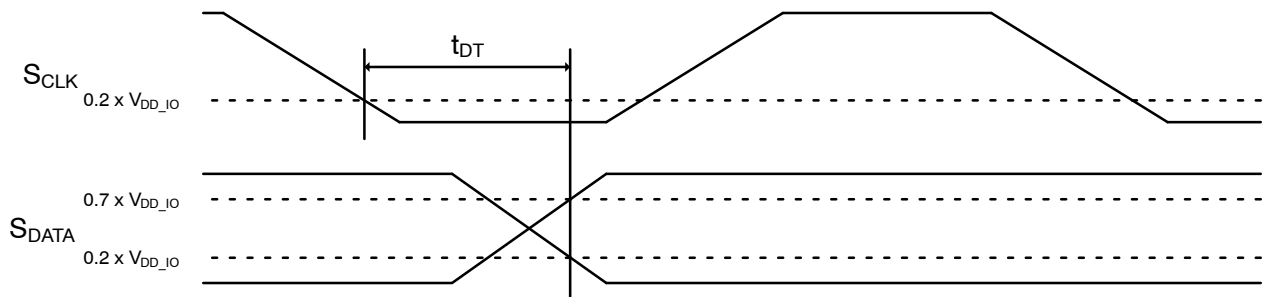


Figure 43. SPI Timing Diagram – Data Input

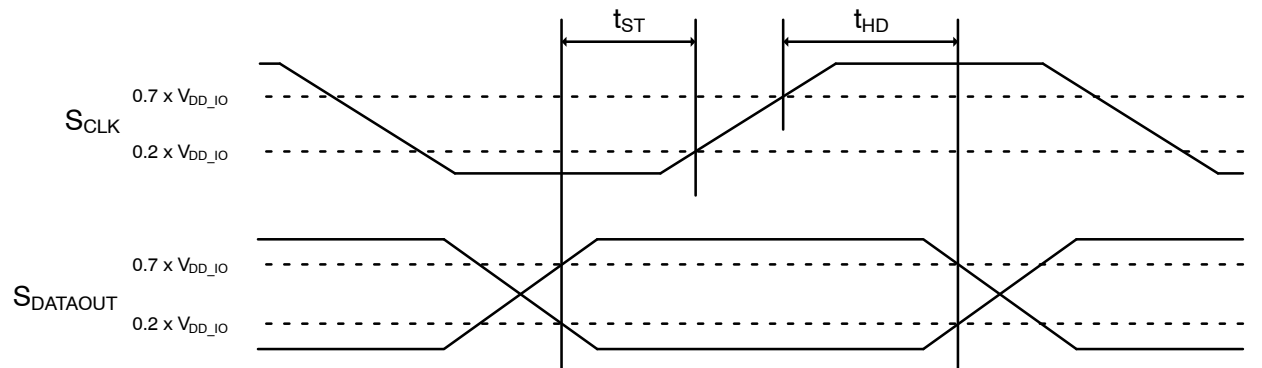


Figure 44. SPI Timing Diagram – Data Output

Table 13. SPI TIMING PARAMETERS

Parameter	Symbol	Min	Typ	Max	Unit
SPI Read Frequency (PLL disabled / PLL enabled)	$f_{\text{SCLK}}$		3.5 / 6.1		MHz
SPI Write Frequency (PLL disabled / PLL enabled)	$f_{\text{SCLK}}$		12.5 / 25		MHz
Setup Time	$t_{\text{ST}}$	$(1/f_{\text{SCLK}})*0.1$			ns
Hold Time	$t_{\text{HD}}$	$(1/f_{\text{SCLK}})*0.1$			ns
Transfer Delay Time	$t_{\text{DT}}$			$(1/f_{\text{SCLK}})*0.5$	ns

## I/O TIMING

## External Clock

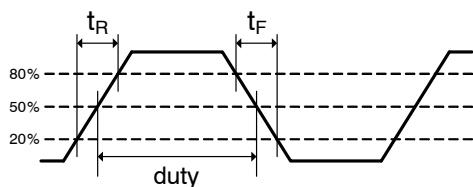


Figure 45. External Clock Timing

Table 14. EXTERNAL CLOCK SPECIFICATIONS

Parameter	Name	Min	Typ	Max	Unit
Clock Frequency	EXTCLK	29 (Note 8)	32.4	36 (Note 8)	MHz
Duty Cycle	Duty	45	50	55	%
Jitter	Jitter	—	—	100	ps
Rise Time	$T_R$	—	—	5	ns
Fall Time	$T_F$	—	—	5	ns

8. Any deviation from the typical EXTCLK frequency needs to be compensated by reconfiguring the internal PLL (guidelines available upon request).

## Trigger Input

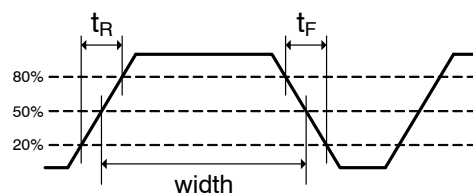


Figure 46. Trigger Input Pulse Timing

Table 15. TRIGGER INPUT PULSE SPECIFICATIONS

Parameter	Symbol	Min	Typ	Max	Unit
Pulse Width	width	100	—	—	ns
Rise Time	$T_R$	—	—	5	ns
Fall Time	$T_F$	—	—	5	ns

## DC ELECTRICAL CHARACTERISTICS

The DC electrical characteristics of the XGS 12000/8000 sensor are listed in Tables 16 through 28.

**Table 16. DC ELECTRICAL CHARACTERISTICS**

Symbol	Definition	Condition	Min	Typ	Max	Unit
V <sub>DD</sub>	Core Digital Voltage		1.1	1.2	1.3	V
V <sub>DD_IO</sub>	I/O Digital Voltage		1.7 / 2.7	1.8 / 2.8	1.9 / 2.9	V
V <sub>AA</sub>	Analog Voltage	Dedicated Power Supply	2.7	2.8	2.9	V
V <sub>AA_PIX</sub>	Pixel Supply Voltage		2.9	3	3.1	V
V <sub>AA_PIX_BST</sub>	Pixel Booster Supply		2.9	3	3.1	V
V <sub>AA_RD</sub>	Row Driver Supply		2.9	3	3.1	V
V <sub>DD_SLVS</sub>	HiSPi Supply Voltage		0.3 / 1.1	0.4 / 1.2	0.5 / 1.3	V
V <sub>DD_PLL</sub>	PLL Supply Voltage		2.7	2.8	2.9	V
V <sub>IH</sub>	Input HIGH Voltage		V <sub>DD_IO</sub> * 0.7	—	V <sub>DD_IO</sub> + 0.5	V
V <sub>IL</sub>	Input LOW Voltage		–0.5	—	V <sub>DD_IO</sub> * 0.3	V
V <sub>OH</sub>	Output HIGH Voltage		V <sub>DD_IO</sub> – 0.3	—	—	V
V <sub>OL</sub>	Output LOW voltage	V <sub>DD_IO</sub> = 2.8V	—	—	0.4	V

CAUTION: Stresses greater than those listed in Table 17 below may cause permanent damage to the device. This is a stress rating only, and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

**Table 17. ABSOLUTE MAXIMUM RATINGS**

Symbol	Parameter	Min	Max	Unit
ABS V <sub>DD_SLVS</sub>	ABS Rating for 0.4 V/1.2 V Supply	–0.5	1.5	V
ABS V <sub>DD</sub>	ABS Rating for 1.2 V Supply	–0.5	1.5	V
ABS V <sub>DD_IO</sub>	ABS Rating for 1.8 V/2.8 V Supply	–0.5	3.2	V
ABS V <sub>DD_PLL</sub>	ABS Rating for 2.8 V Supply	–0.5	3.2	V
ABS V <sub>AA</sub>	ABS Rating for 2.8 V Supply	–0.5	3.2	V
ABS V <sub>AA_PIX</sub> , V <sub>AA_RD</sub> , V <sub>AA_PIX_BST</sub>	ABS Rating for 3.0 V Supply	–0.5	3.6	V
T <sub>STG</sub>	ABS Storage Temperature Range	–40	+150	°C
	ABS Storage Humidity Range at 85°C		85	%RH
Electrostatic Discharge (ESD) (ANSI / ESDA / JEDEC Standard)	Human Body Model (HBM): JS–001–2014	2000		V
	Charged Device Model (CDM): JS–002–2014	500		
LU	Latch-Up: JESD–78	100		mA

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

9. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

10. Operating ratings are conditions in which operation of the device is intended to be functional.

11. ON Semiconductor recommends that customers become familiar with, and follow the procedures in JEDEC Standard JESD625–A. Refer to (AN52561/D). Long term exposure toward the maximum storage temperature will accelerate color filter degradation.

12. Caution needs to be taken to avoid dried stains on the underside of the glass due to condensation. The glass lid glue is permeable and can absorb moisture if the sensor is placed in a high % RH environment.



**Table 18. OPERATING CURRENT CONSUMPTION (XGS 5000–X4)**

( $V_{AA\_PIX} = V_{AA\_PIX\_BST} = V_{AA\_RD} = 3.0\text{ V}$ ;  $V_{AA} = V_{DD\_PLL} = 2.8\text{ V}$ ;  $V_{DD\_IO} = 1.8\text{ V}$ ;  $V_{DD} = 1.2\text{ V}$ ;  $V_{DD\_SLVS} = 0.4\text{ V}/1.2\text{ V}$ ;  
 $T_A = 25^\circ\text{C}$ )

Symbol	Parameter	Condition	Min	Typ	Max	Unit
$I_{DD}$	Digital Operating Current	TBD	–	TBD	TBD	mA
$I_{DD\_IO}$	I/O Digital Operating Current	TBD	–	TBD	TBD	mA
$I_{AA}$	Analog Operating Current	TBD	–	TBD	TBD	mA
$I_{AA\_PIX}$	Pixel Supply Current	TBD	–	TBD	TBD	mA
$I_{AA\_PIX\_BST}$	Pixel Booster Supply Current	TBD	–	TBD	TBD	mA
$I_{AA\_RD}$	Row Driver Supply Current	TBD	–	TBD	TBD	mA
$I_{DD\_SLVS}$	HiSPi Supply Current	TBD	–	TBD	TBD	mA
$I_{DD\_PLL}$	PLL Supply Current	TBD	–	TBD	TBD	mA

**Table 19. OPERATING CURRENT CONSUMPTION (XGS 5000–X5)**

( $V_{AA\_PIX} = V_{AA\_PIX\_BST} = V_{AA\_RD} = 3.0\text{ V}$ ;  $V_{AA} = V_{DD\_PLL} = 2.8\text{ V}$ ;  $V_{DD\_IO} = 1.8\text{ V}$ ;  $V_{DD} = 1.2\text{ V}$ ;  $V_{DD\_SLVS} = 0.4\text{ V}/1.2\text{ V}$ ;  
 $T_A = 25^\circ\text{C}$ )

Symbol	Parameter	Condition	Min	Typ	Max	Unit
$I_{DD}$	Digital Operating Current	TBD	–	TBD	TBD	mA
$I_{DD\_IO}$	I/O Digital Operating Current	TBD	–	TBD	TBD	mA
$I_{AA}$	Analog Operating Current	TBD	–	TBD	TBD	mA
$I_{AA\_PIX}$	Pixel Supply Current	TBD	–	TBD	TBD	mA
$I_{AA\_PIX\_BST}$	Pixel Booster Supply Current	TBD	–	TBD	TBD	mA
$I_{AA\_RD}$	Row Driver Supply Current	TBD	–	TBD	TBD	mA
$I_{DD\_SLVS}$	HiSPi Supply Current	TBD	–	TBD	TBD	mA
$I_{DD\_PLL}$	PLL Supply Current	TBD	–	TBD	TBD	mA

**Table 20. OPERATING CURRENT CONSUMPTION (XGS 3000–X4)**

( $V_{AA\_PIX} = V_{AA\_PIX\_BST} = V_{AA\_RD} = 3.0\text{ V}$ ;  $V_{AA} = V_{DD\_PLL} = 2.8\text{ V}$ ;  $V_{DD\_IO} = 1.8\text{ V}$ ;  $V_{DD} = 1.2\text{ V}$ ;  $V_{DD\_SLVS} = 0.4\text{ V}/1.2\text{ V}$ ;  
 $T_A = 25^\circ\text{C}$ )

Symbol	Parameter	Condition	Min	Typ	Max	Unit
$I_{DD}$	Digital Operating Current	TBD	–	TBD	TBD	mA
$I_{DD\_IO}$	I/O Digital Operating Current	TBD	–	TBD	TBD	mA
$I_{AA}$	Analog Operating Current	TBD	–	TBD	TBD	mA
$I_{AA\_PIX}$	Pixel Supply Current	TBD	–	TBD	TBD	mA
$I_{AA\_PIX\_BST}$	Pixel Booster Supply Current	TBD	–	TBD	TBD	mA
$I_{AA\_RD}$	Row Driver Supply Current	TBD	–	TBD	TBD	mA
$I_{DD\_SLVS}$	HiSPi Supply Current	TBD	–	TBD	TBD	mA
$I_{DD\_PLL}$	PLL Supply Current	TBD	–	TBD	TBD	mA

**Table 21. OPERATING CURRENT CONSUMPTION (XGS 3000–X5)**

( $V_{AA\_PIX} = V_{AA\_PIX\_BST} = V_{AA\_RD} = 3.0\text{ V}$ ;  $V_{AA} = V_{DD\_PLL} = 2.8\text{ V}$ ;  $V_{DD\_IO} = 1.8\text{ V}$ ;  $V_{DD} = 1.2\text{ V}$ ;  $V_{DD\_SLVS} = 0.4\text{ V}/1.2\text{ V}$ ;  
 $T_A = 25^\circ\text{C}$ )

Symbol	Parameter	Condition	Min	Typ	Max	Unit
$I_{DD}$	Digital Operating Current	TBD	–	TBD	TBD	mA
$I_{DD\_IO}$	I/O Digital Operating Current	TBD	–	TBD	TBD	mA
$I_{AA}$	Analog Operating Current	TBD	–	TBD	TBD	mA
$I_{AA\_PIX}$	Pixel Supply Current	TBD	–	TBD	TBD	mA
$I_{AA\_PIX\_BST}$	Pixel Booster Supply Current	TBD	–	TBD	TBD	mA
$I_{AA\_RD}$	Row Driver Supply Current	TBD	–	TBD	TBD	mA
$I_{DD\_SLVS}$	HiSPi Supply Current	TBD	–	TBD	TBD	mA
$I_{DD\_PLL}$	PLL Supply Current	TBD	–	TBD	TBD	mA

**Table 22. OPERATING CURRENT CONSUMPTION (XGS 2000–X4)**

( $V_{AA\_PIX} = V_{AA\_PIX\_BST} = V_{AA\_RD} = 3.0\text{ V}$ ;  $V_{AA} = V_{DD\_PLL} = 2.8\text{ V}$ ;  $V_{DD\_IO} = 1.8\text{ V}$ ;  $V_{DD} = 1.2\text{ V}$ ;  $V_{DD\_SLVS} = 0.4\text{ V}/1.2\text{ V}$ ;  
 $T_A = 25^\circ\text{C}$ )

Symbol	Parameter	Condition	Min	Typ	Max	Unit
$I_{DD}$	Digital Operating Current	TBD	–	TBD	TBD	mA
$I_{DD\_IO}$	I/O Digital Operating Current	TBD	–	TBD	TBD	mA
$I_{AA}$	Analog Operating Current	TBD	–	TBD	TBD	mA
$I_{AA\_PIX}$	Pixel Supply Current	TBD	–	TBD	TBD	mA
$I_{AA\_PIX\_BST}$	Pixel Booster Supply Current	TBD	–	TBD	TBD	mA
$I_{AA\_RD}$	Row Driver Supply Current	TBD	–	TBD	TBD	mA
$I_{DD\_SLVS}$	HiSPi Supply Current	TBD	–	TBD	TBD	mA
$I_{DD\_PLL}$	PLL Supply Current	TBD	–	TBD	TBD	mA

**Table 23. OPERATING CURRENT CONSUMPTION (XGS 2000–X5)**

( $V_{AA\_PIX} = V_{AA\_PIX\_BST} = V_{AA\_RD} = 3.0\text{ V}$ ;  $V_{AA} = V_{DD\_PLL} = 2.8\text{ V}$ ;  $V_{DD\_IO} = 1.8\text{ V}$ ;  $V_{DD} = 1.2\text{ V}$ ;  $V_{DD\_SLVS} = 0.4\text{ V}/1.2\text{ V}$ ;  
 $T_A = 25^\circ\text{C}$ )

Symbol	Parameter	Condition	Min	Typ	Max	Unit
$I_{DD}$	Digital Operating Current	TBD	–	145	240	mA
$I_{DD\_IO}$	I/O Digital Operating Current	TBD	–	5	10	mA
$I_{AA}$	Analog Operating Current	TBD	–	100	180	mA
$I_{AA\_PIX}$	Pixel Supply Current	TBD	–	20	40	mA
$I_{AA\_PIX\_BST}$	Pixel Booster Supply Current	TBD	–	20	35	mA
$I_{AA\_RD}$	Row Driver Supply Current	TBD	–	0	10	mA
$I_{DD\_SLVS}$	HiSPi Supply Current		–	60 / 115	85 / 150	mA
$I_{DD\_PLL}$	PLL Supply Current	TBD	–	10	20	mA

**Table 24. OPERATING CURRENT CONSUMPTION (XGS 1300–X4)**

(V<sub>AA\_PIX</sub> = V<sub>AA\_PIX\_BST</sub> = V<sub>AA\_RD</sub> = 3.0 V; V<sub>AA</sub> = V<sub>DD\_PLL</sub> = 2.8 V; V<sub>DD\_IO</sub> = 1.8 V; V<sub>DD</sub> = 1.2 V; V<sub>DD\_SLVS</sub> = 0.4 V/1.2 V;  
T<sub>A</sub> = 25°C)

Symbol	Parameter	Condition	Min	Typ	Max	Unit
I <sub>DD</sub>	Digital Operating Current	TBD	–	TBD	TBD	mA
I <sub>DD_IO</sub>	I/O Digital Operating Current	TBD	–	TBD	TBD	mA
I <sub>AA</sub>	Analog Operating Current	TBD	–	TBD	TBD	mA
I <sub>AA_PIX</sub>	Pixel Supply Current	TBD	–	TBD	TBD	mA
I <sub>AA_PIX_BST</sub>	Pixel Booster Supply Current	TBD	–	TBD	TBD	mA
I <sub>AA_RD</sub>	Row Driver Supply Current	TBD	–	TBD	TBD	mA
I <sub>DD_SLVS</sub>	HiSPi Supply Current	TBD	–	TBD	TBD	mA
I <sub>DD_PLL</sub>	PLL Supply Current	TBD	–	TBD	TBD	mA

**Table 25. STANDBY CURRENT CONSUMPTION**

(V<sub>AA\_PIX</sub> = V<sub>AA\_PIX\_BST</sub> = V<sub>AA\_RD</sub> = 3.0 V; V<sub>AA</sub> = V<sub>DD\_PLL</sub> = 2.8 V; V<sub>DD\_IO</sub> = 1.8 V; V<sub>DD</sub> = 1.2 V; V<sub>DD\_SLVS</sub> = 0.4 V / 1.2 V;  
T<sub>A</sub> = 25°C)

Sensor State	Condition	Min	Typ	Max	Unit
WAIT_ON_TRIGGER	V <sub>DD_SLVS</sub> (0.4 V / 1.2 V)	–	75 / 135	–	μA
	V <sub>DD</sub> (1.2 V)	–	170	–	μA
	V <sub>DD_IO</sub> (1.8 V)	–	5	–	μA
	V <sub>DD_PLL</sub> (2.8 V)	–	10	–	μA
	V <sub>AA</sub> (2.8 V)	–	130	–	μA
	V <sub>AA_PIX</sub> (3.0 V)	–	25	–	μA
	V <sub>AA_PIX_BST</sub> (3.0 V)	–	30	–	μA
	V <sub>AA_RD</sub> (3.0 V)	–	5	–	μA
STANDBY	V <sub>DD_SLVS</sub> (0.4 V / 1.2 V)	–	75 / 135	–	μA
	V <sub>DD</sub> (1.2 V)	–	170	–	μA
	V <sub>DD_IO</sub> (1.8 V)	–	5	–	μA
	V <sub>DD_PLL</sub> (2.8 V)	–	10	–	μA
	V <sub>AA</sub> (2.8 V)	–	20	–	μA
	V <sub>AA_PIX</sub> (3.0 V)	–	0	–	μA
	V <sub>AA_PIX_BST</sub> (3.0 V)	–	15	–	μA
	V <sub>AA_RD</sub> (3.0 V)	–	0	–	μA
SLEEP	V <sub>DD_SLVS</sub> (0.4 V / 1.2 V)	–	55 / 100	–	μA
	V <sub>DD</sub> (1.2 V)	–	40	–	μA
	V <sub>DD_IO</sub> (1.8 V)	–	5	–	μA
	V <sub>DD_PLL</sub> (2.8 V)	–	0	–	μA
	V <sub>AA</sub> (2.8 V)	–	0	–	μA
	V <sub>AA_PIX</sub> (3.0 V)	–	0	–	μA
	V <sub>AA_PIX_BST</sub> (3.0 V)	–	0	–	μA
	V <sub>AA_RD</sub> (3.0 V)	–	0	–	μA

**Table 25. STANDBY CURRENT CONSUMPTION**

( $V_{AA\_PIX} = V_{AA\_PIX\_BST} = V_{AA\_RD} = 3.0\text{ V}$ ;  $V_{AA} = V_{DD\_PLL} = 2.8\text{ V}$ ;  $V_{DD\_IO} = 1.8\text{ V}$ ;  $V_{DD} = 1.2\text{ V}$ ;  $V_{DD\_SLVS} = 0.4\text{ V} / 1.2\text{ V}$ ;  
 $T_A = 25^\circ\text{C}$ )

Sensor State	Condition	Min	Typ	Max	Unit
RESET	$V_{DD\_SLVS}$ (0.4 V / 1.2 V)	–	55 / 100	–	$\mu\text{A}$
	$V_{DD}$ (1.2 V)	–	10	–	$\mu\text{A}$
	$V_{DD\_IO}$ (1.8 V)	–	5	–	$\mu\text{A}$
	$V_{DD\_PLL}$ (2.8 V)	–	0	–	$\mu\text{A}$
	$V_{AA}$ (2.8 V)	–	0	–	$\mu\text{A}$
	$V_{AA\_PIX}$ (3.0 V)	–	0	–	$\mu\text{A}$
	$V_{AA\_PIX\_BST}$ (3.0 V)	–	0	–	$\mu\text{A}$
	$V_{AA\_RD}$ (3.0 V)	–	0	–	$\mu\text{A}$

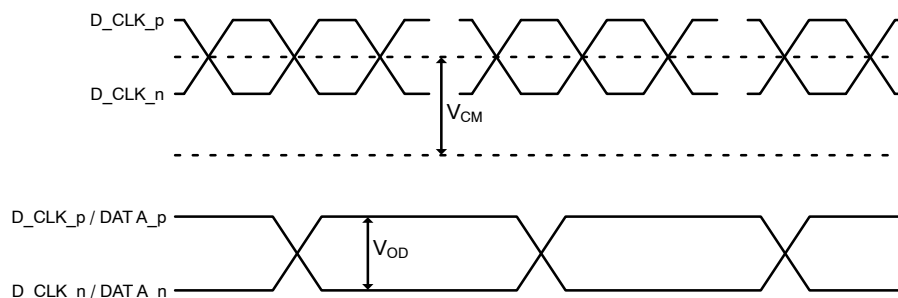
### HISPI ELECTRICAL SPECIFICATION

The XGS sensor from ON Semiconductor supports SLVS mode only. SLVS is typically meant only for short transmission line connections, with the advantage that SLVS drivers consume less power. Refer to the HiSPi Physical Layer Specification v2.00.00 ([AND9509/D](#)) for additional electrical definitions, specifications and timing information. Note that the  $V_{DD\_SLVS}$  supply in this datasheet corresponds to  $V_{DD\_TX}$  in the HiSPi Physical Layer Specification. Similarly,  $V_{DD\_IO}$  is equivalent to  $V_{DD\_HiSPi}$  as referenced in the specification.

Table 4 in the HiSPi Physical Layer specification v2.00.00 ([AND9509/D](#)) document sets the maximum

PHY-to-PHY skew to 2.1 UI. The XGS products adhere to this specification when looking at all HiSPi data and HiSPi clock lanes on the same side of the sensor. The maximum PHY-to-PHY skew between any odd clock lane and any odd data lane is 2.1 UI. The same holds for the skew between any even clock lane and any even data lane.

However the maximum PHY-to-PHY skew between any odd clock lane and any even data lane, or between any even clock lane and any odd data lane, can be maximum 4 pixels. The maximum value for this depends on the mux mode that is used. In 4:4 mux mode, the maximum is 1 pixel. In 4:2 mux mode, the maximum is 2 pixels. And in 4:1 mux mode, the maximum is 4 pixels.



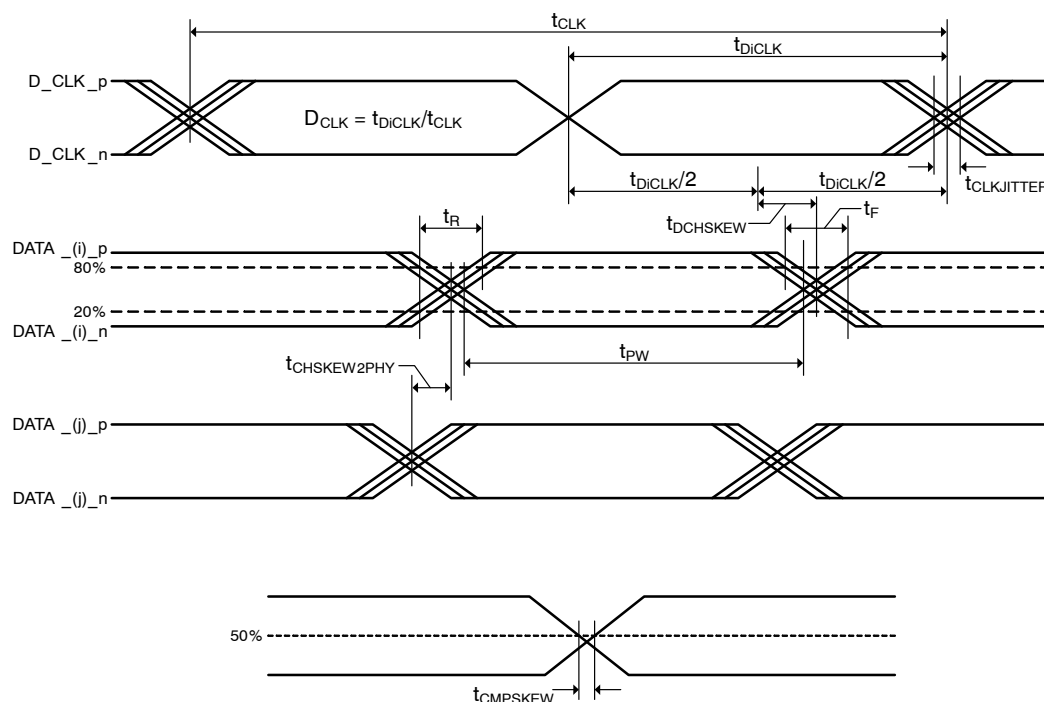
**Figure 47. HiSPi DC Parameters**

**Table 26. HISPI DC SPECIFICATIONS** ( $V_{DD\_SLVS} = 0.4\text{ V}$ )

Symbol	Parameter	Min	Typ	Max	Unit
$V_{DD\_SLVS}$	HiSPi Power Supply	0.35	0.4	0.45	V
$V_{OD}$	Input Differential Voltage ( $R_{IN} = 100\ \Omega$ )	$0.4 * V_{DD\_SLVS}$	$0.5 * V_{DD\_SLVS}$	$0.6 * V_{DD\_SLVS}$	V
$V_{CM}$	Input Common Mode Range ( $R_{IN} = 100\ \Omega$ )	$0.45 * V_{DD\_SLVS}$	$0.5 * V_{DD\_SLVS}$	$0.55 * V_{DD\_SLVS}$	V
$R_{IN}$	Termination Resistor		100		$\Omega$
Output Impedance	Output Impedance per Pin	35	50	70	$\Omega$

**Table 27. DIFFERENTIAL DATA OUTPUT DC SPECIFICATIONS** ( $V_{DD\_SLVS} = 1.2\text{ V}$ )

Symbol	Parameter	Min	Typ	Max	Unit
$V_{DD\_SLVS}$	HiSPi Power Supply	1.1	1.2	1.3	V
$V_{OD}$	Input Differential Voltage ( $R_{IN} = 100\ \Omega$ )	0.3	0.35	0.4	V
$V_{CM}$	Input Common Mode Range ( $R_{IN} = 100\ \Omega$ )	0.3	0.35	0.4	V
$R_{IN}$	Termination Resistor		100		$\Omega$
Output Impedance	Output Impedance per Pin	35	50	70	$\Omega$

**Figure 48. Differential Data Output AC Parameters****Table 28. DIFFERENTIAL DATA OUTPUT AC SPECIFICATIONS** ( $V_{DD\_SLVS} = 0.4\text{ V}, 1.2\text{ V}$ )

Parameter	Symbol	Min	Typ	Max	Unit
Data Rate	$1/t_{DICLK}$	—	777.6	—	Mbps
Clock Period	$t_{CLK}$	—	2.57	—	ns
Data Period	$t_{DICLK}$	—	1.28	—	ns
Data Eye Width	$t_{PW}$	0.6	0.8	—	UI
Clock Jitter	$t_{CLKJITTER}$	—	40	50	ps
Rise Time	$t_R$	—	310	—	ps
Fall Time	$t_F$	—	310	—	ps
Clock Duty	$D_{CLK}$	42	—	58	%
Clock to Data Skew within any PHY	$t_{DCHSKEW}$	−0.1	—	0.1	UI
Skew between any Two PHY Clocks	$t_{CHSKEW2PHY}$	−2.3	—	2.3	UI
Complementary Skew in Differential Pair	$t_{CMPSKEW}$	−100	—	100	ps

13.1 UI is defined as the normalized mean time between one edge and the following edge of the clock.

## IMAGE SENSOR CHARACTERISTICS

### ELECTRO–OPTICAL SPECIFICATIONS

An overview of the XGS key electro–optical specifications can be found in Table 29. Unless otherwise noted, all measurements were done using the recommended configuration and default operation mode.

### SPECTRAL RESPONSE

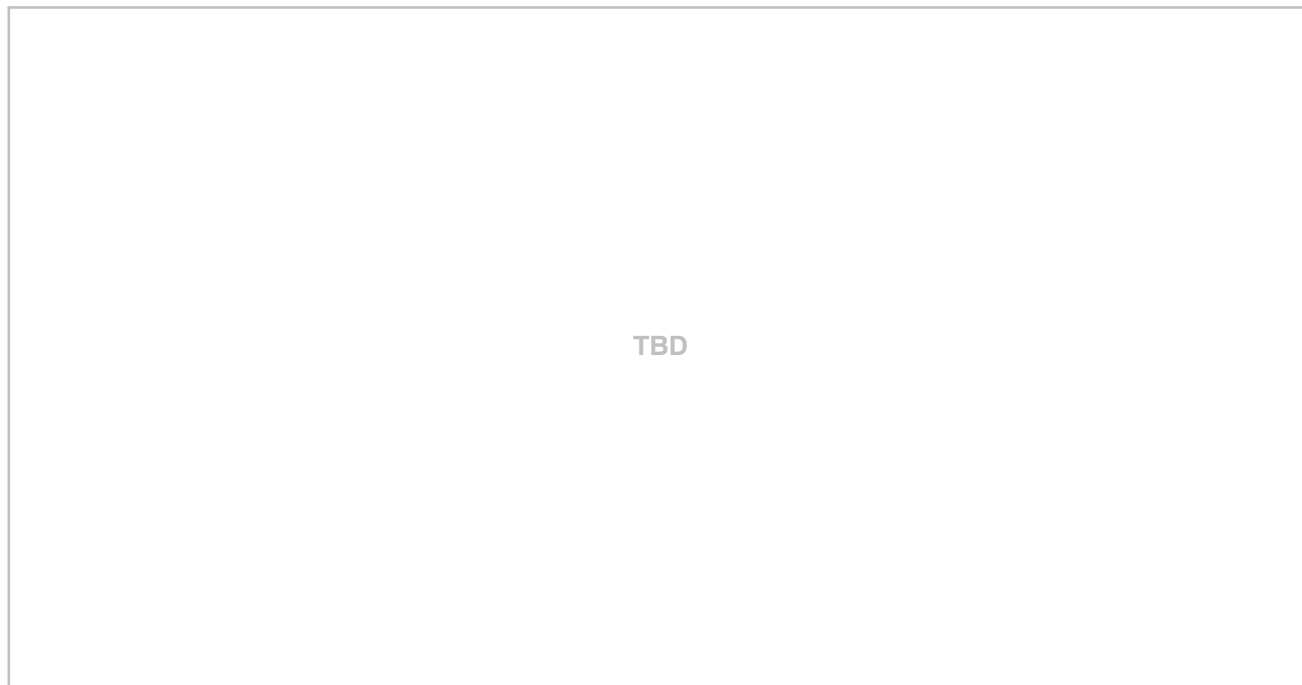
Quantum efficiency curves are measured using a monochromator with step size of 5 nm. The curves for monochrome and color devices are shown in Figure 49.

**Table 29. ELECTRO–OPTICAL SPECIFICATIONS**

Parameter	Specification
Quantum Efficiency (Note 14)	TBD
	TBD
Column FPN	TBD
Column Temporal Noise	TBD
Row FPN	TBD
Row Temporal Noise	TBD
Dark Current	80 e <sub>-</sub> /s (T <sub>j</sub> = 60°C)
DSNU	TBD
PRNU	0.5% *
Shutter Efficiency	TBD
MTF	TBD

\*Preliminary values subject to change

14. Measured on devices with cover glass (typical transmittance cover glass = 91%).



**Figure 49. Quantum Efficiency (Mono)**

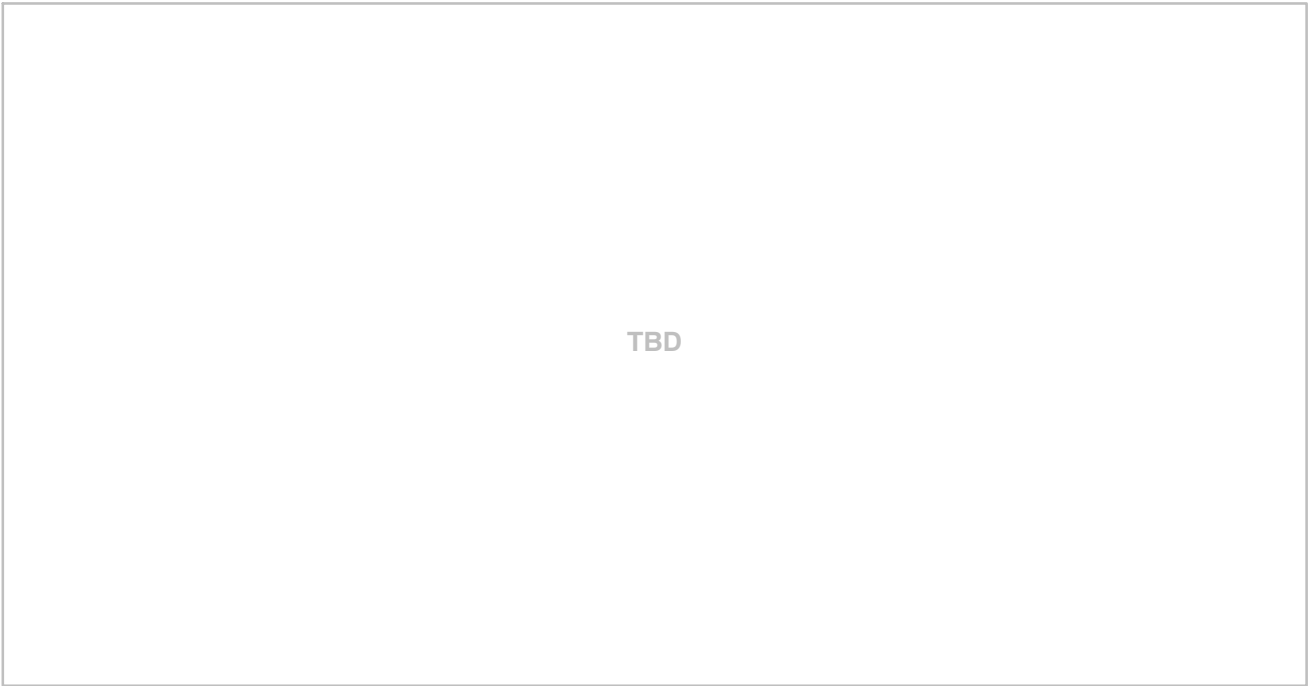


Figure 50. Quantum Efficiency (Color)

COVER GLASS

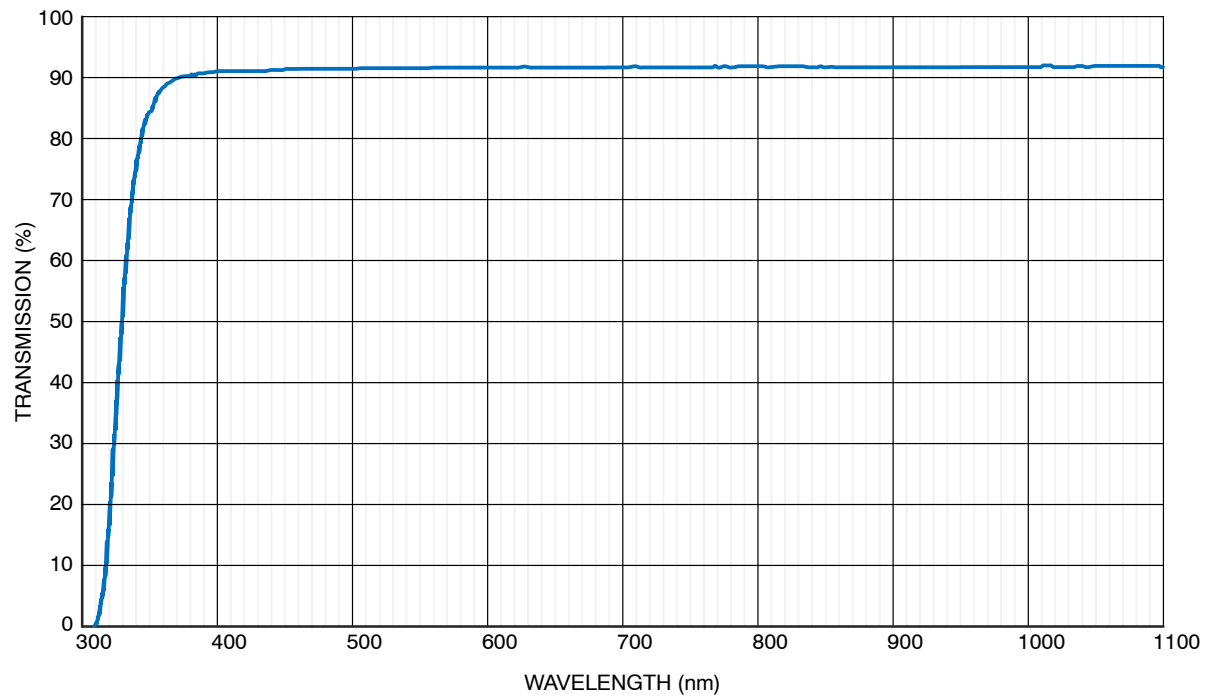


Figure 51. Cover Glass Transmission Curve

Table 30. COVER GLASS SPECIFICATIONS

Parameter	Specification
Material	D263 T-ECO
Refractive Index (@ 550 nm)	1.5255
Luminous Transmittance (@ D65)	91% (0.55 mm Thickness)
Density (@ 40°C)	2.51 g/cm <sup>3</sup>
Linear Thermal Coefficient (20°C – 300°C)	7.2 x 10 <sup>-6</sup> /K

## PACKAGING

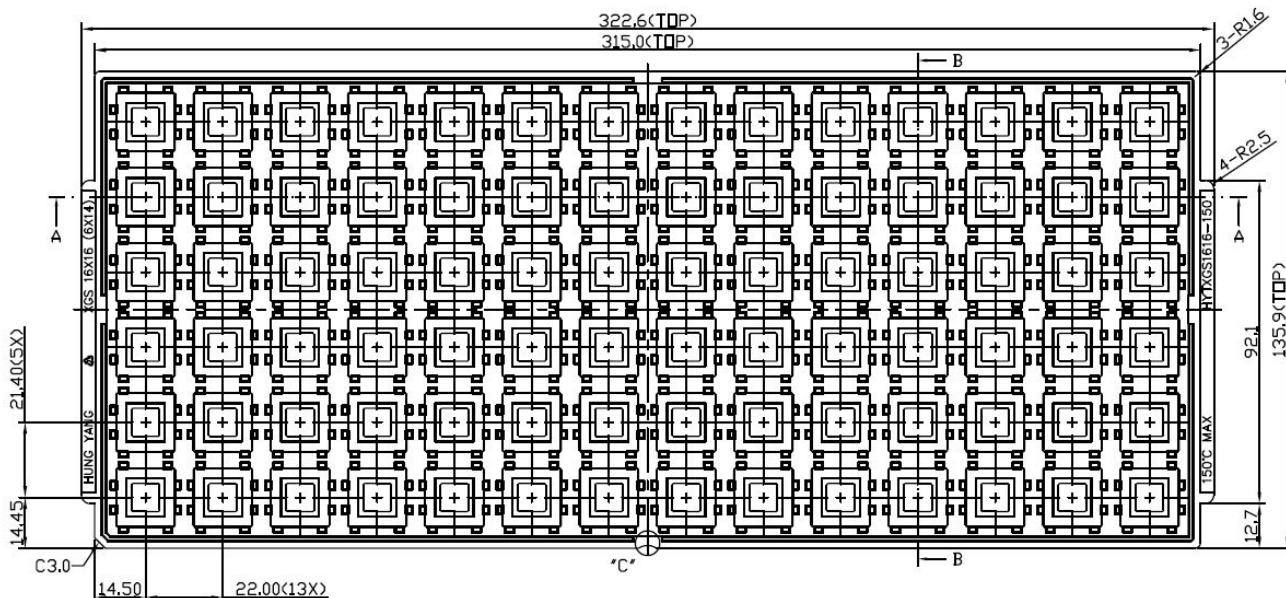


Figure 52. XGS 5000 Shipping Tray – Top View

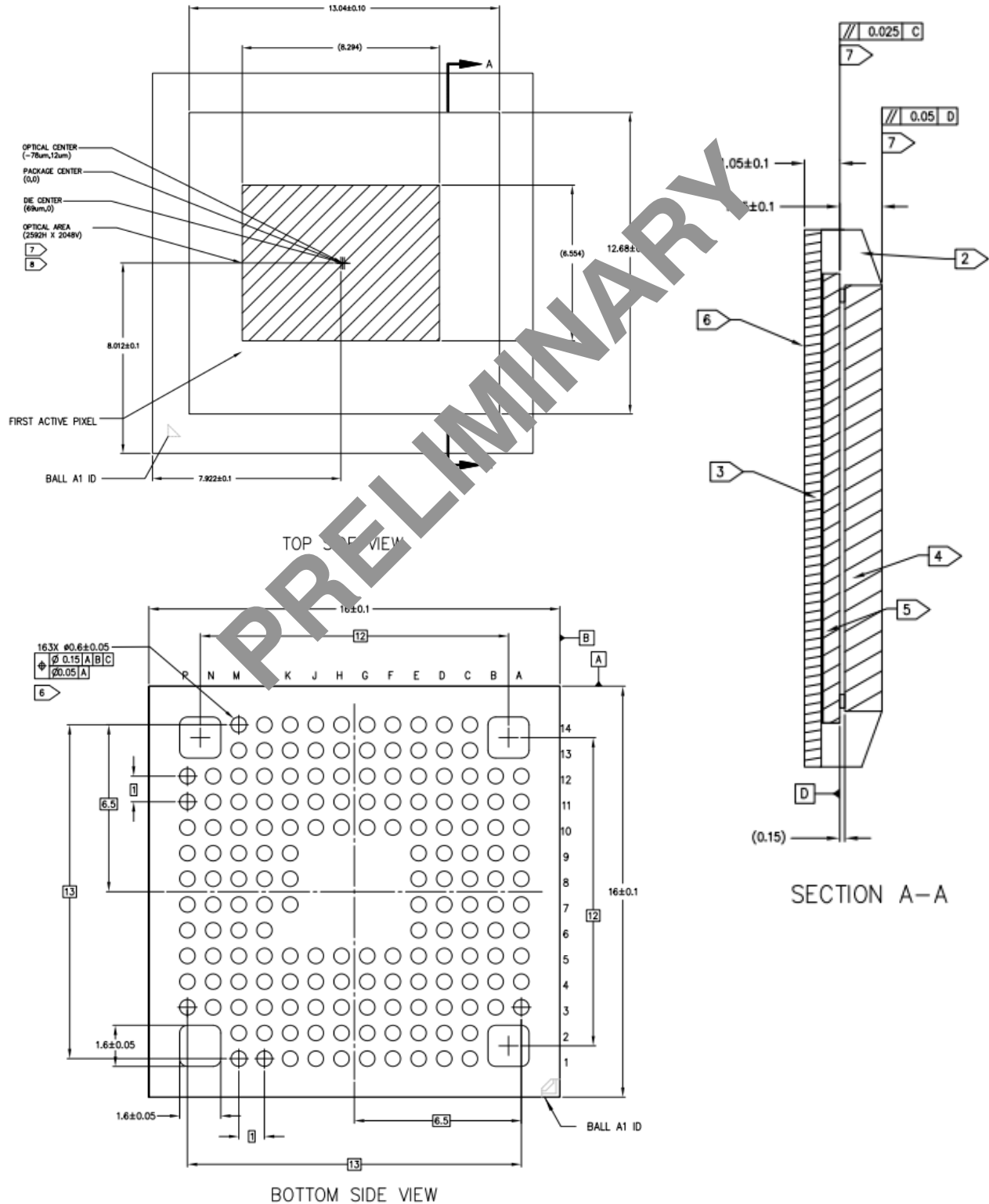
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- [AN52561/D](#). (n.d.). *Image Sensor Handling and Best Practices*
- [AND9509/D](#). (n.d.). *High-Speed Serial Pixel (HiSPi) Interface Physical Layer v2.00.00*
- [AND9510/D](#). (n.d.). *High-Speed Serial Pixel (HiSPi) Interface Protocol*
- [TND310/D](#). (n.d.). *Device Nomenclature (Naming Convention for Image Sensors)*



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